

ECE1371 Advanced Analog Circuits

Lecture 8

COMPARATOR & FLASH ADC DESIGN

Richard Schreier

`richard.schreier@analog.com`

Trevor Caldwell

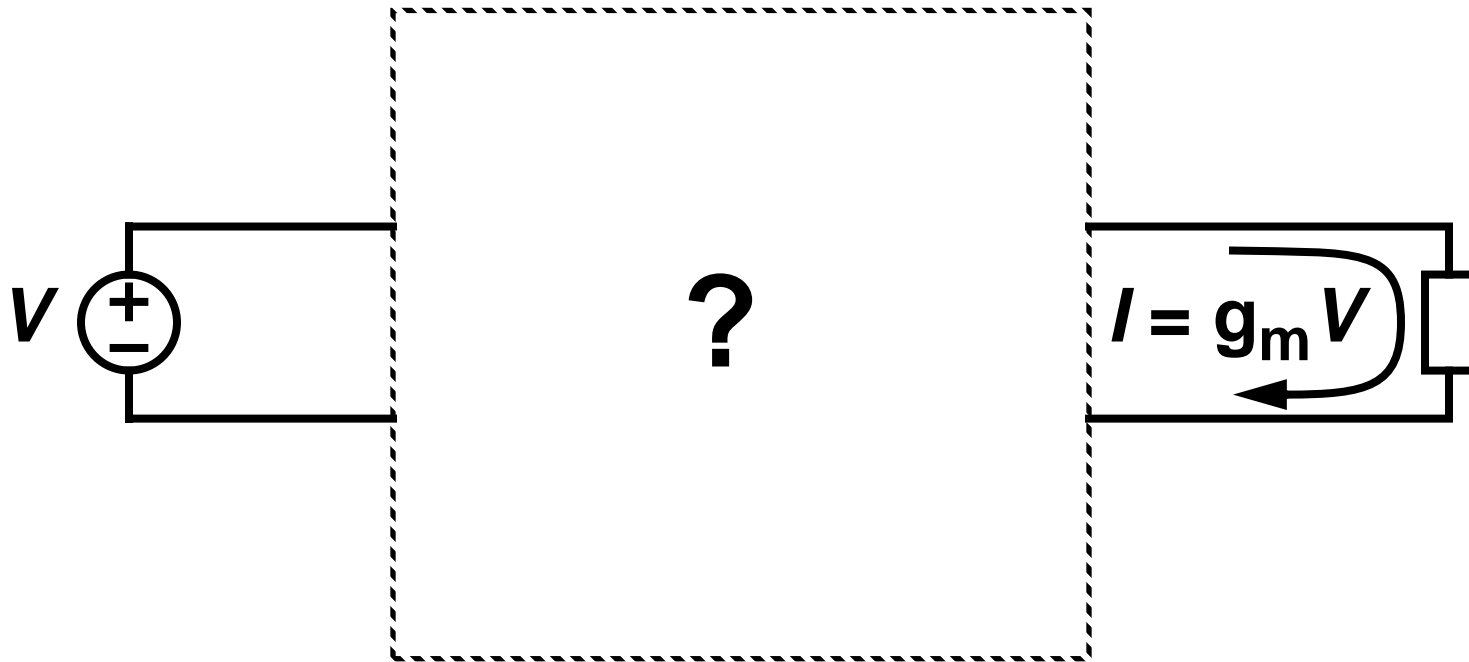
`trevor.caldwell@utoronto.ca`

Course Goals

- **Deepen understanding of CMOS analog circuit design through a top-down study of a modern analog system— a delta-sigma ADC**
- **Develop circuit insight through brief peeks at some nifty little circuits**
 - The circuit world is filled with many little gems that every competent designer ought to know.**

Date	Lecture (M 13:00-15:00)			Ref	Homework
2015-01-05	RS	1	MOD1 & MOD2	ST 2, 3, A	1: Matlab MOD1&2
2015-01-12	RS	2	MODN + $\Delta\Sigma$ Toolbox	ST 4, B	2: $\Delta\Sigma$ Toolbox
2015-01-19	RS	3	Example Design: Part 1	ST 9.1, CCJM 14	3: Sw.-level MOD2
2015-01-26	RS	4	Example Design: Part 2	CCJM 18	
2015-02-02	TC	5	SC Circuits	R 12, CCJM 14	4: SC circuit
2015-02-09	TC	6	Amplifier Design		
2015-02-16	Reading Week– No Lecture				
2015-02-23	TC	7	Amplifier Design		5: SC Int w/ Amp
2015-03-02	RS	8	Comparator & Flash ADC	CCJM 10	Project
2015-03-09	TC	9	Noise in SC Circuits	ST C	
2015-03-16	RS	10	Advanced $\Delta\Sigma$	ST 6.6, 9.4	
2015-03-23	TC	11	Matching & MM-Shaping	ST 6.3-6.5, +	
2015-03-30	TC	12	Pipeline and SAR ADCs	CCJM 15, 17	
2015-04-06	Exam			Proj. Report Due Friday April 10	
2015-04-13	Project Presentation				

NLCOTD: Linear Transconductor



- **Useful in**
 - 1 gm-C filter
 - 2 LNA
 - 3 mixer
 - 4 CT $\Delta\Sigma$ ADC

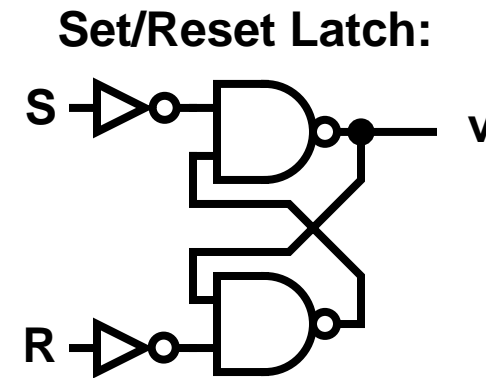
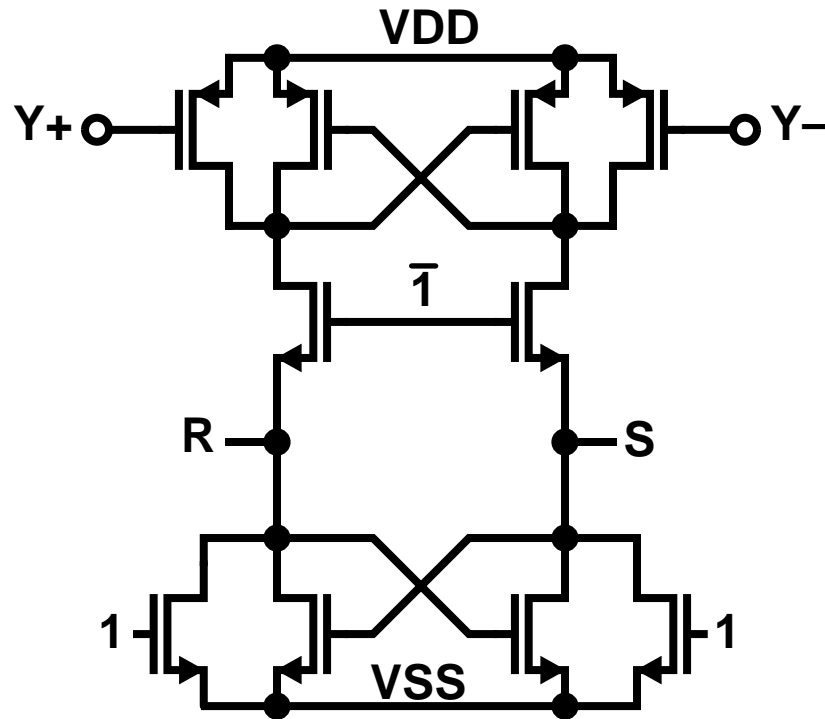
Highlights

(i.e. What you will learn today)

- 1 Operation of Example Comparator Circuit
- 2 Regeneration Time Constant τ
- 3 Metastability, Probability of Error
- 4 Offset, Dynamic Offset, Auto-zeroing
- 5 Flash ADC
- 6 A Bunch of Transconductor Circuits

Review: Latched Comparator

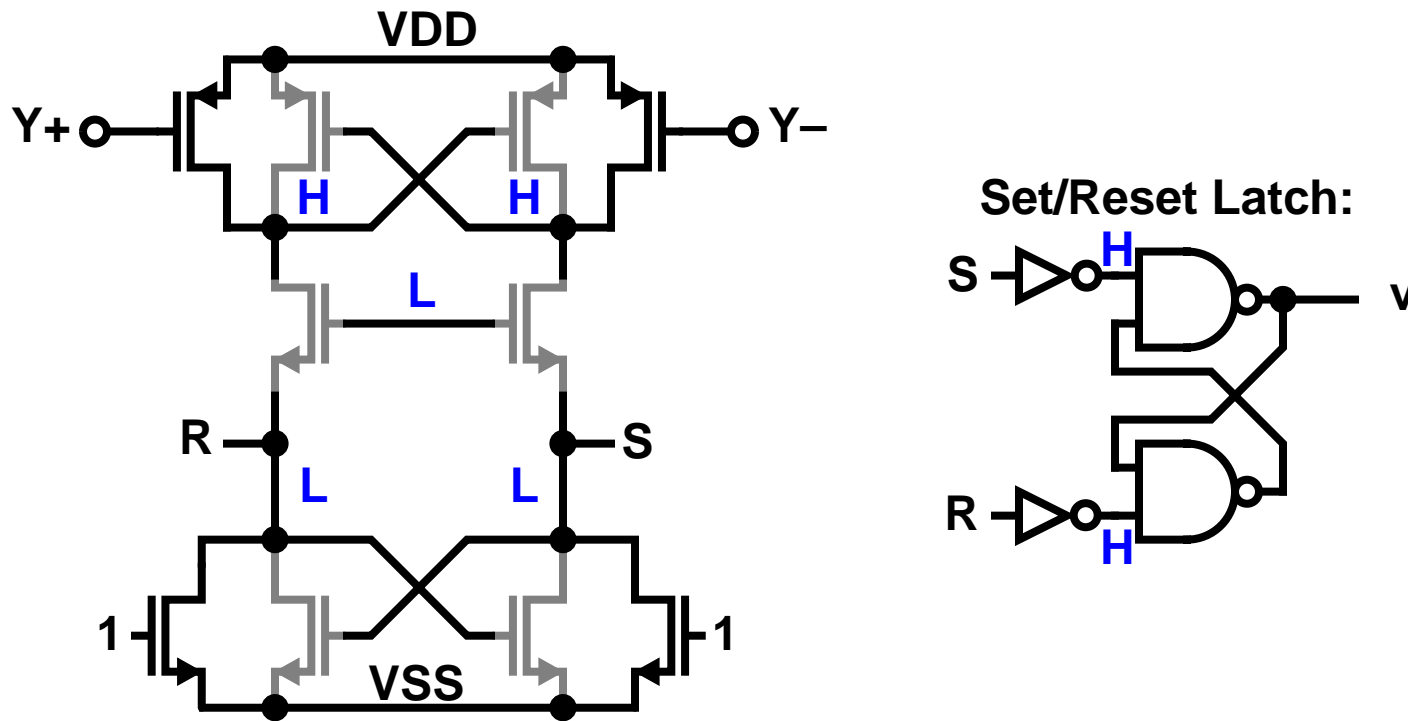
From Lecture #4's 1-MHz MOD2



Inverter thresholds are chosen so that the inverters respond only after R/S have resolved.

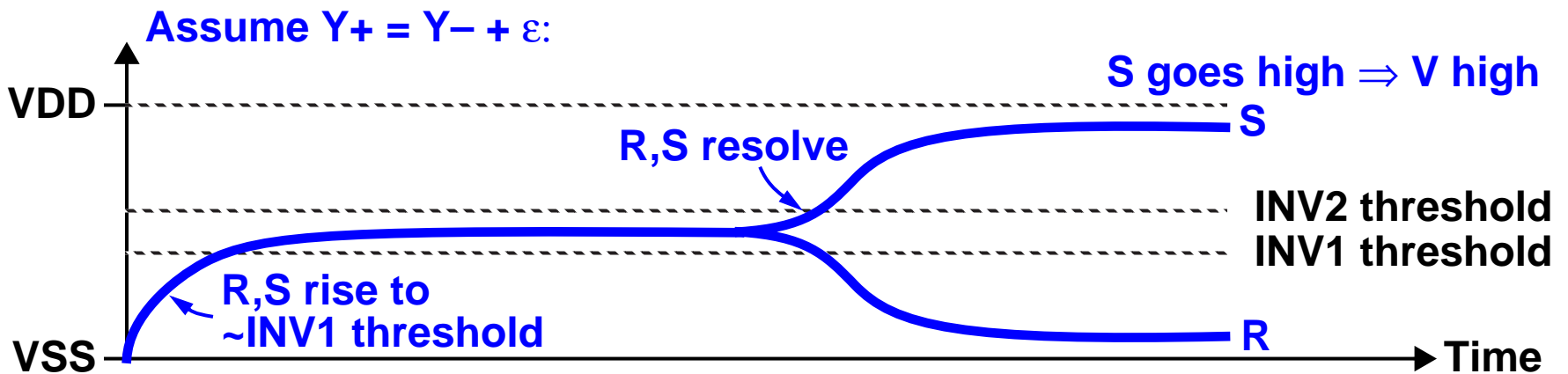
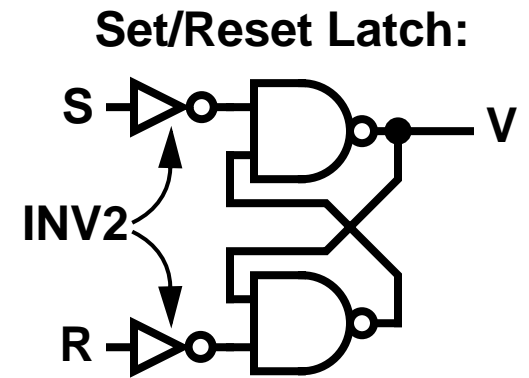
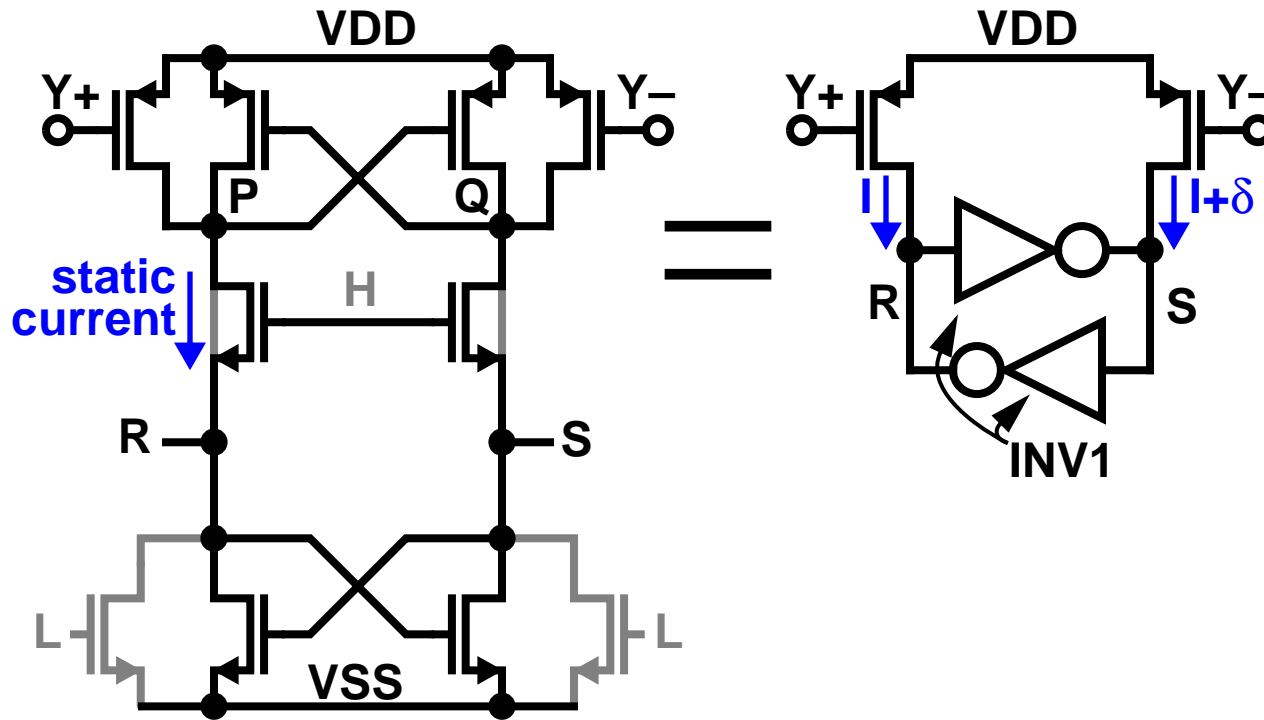
- **Falling phase 1 initiates regenerative action**
S and R connected to a Set/Reset latch.

Phase 1 = High: “Reset” Mode



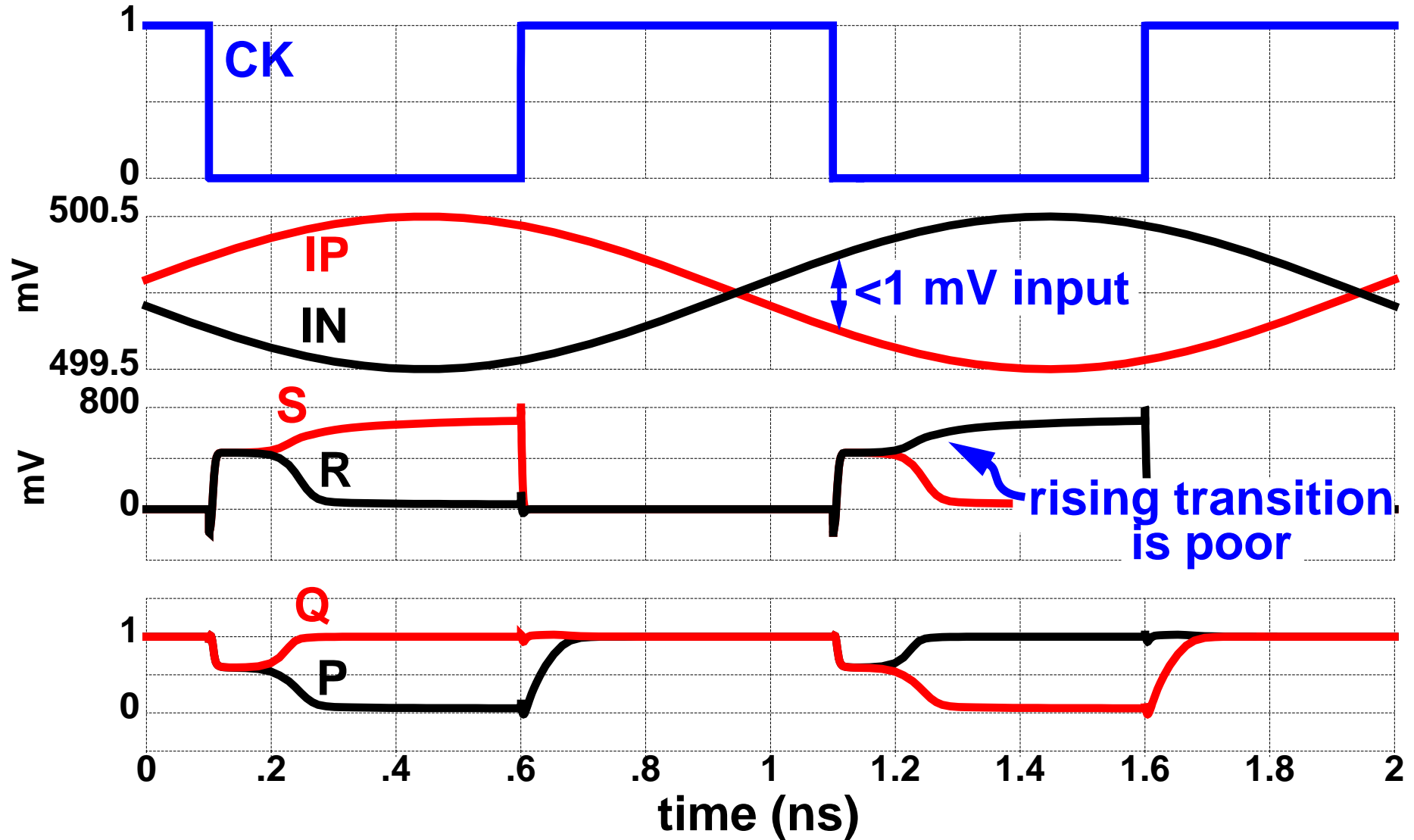
- **Grayed-out devices are off**
⇒ **the active part of the comparator is reset**
- **R and S are low** ⇒ **the SR latch is in hold mode**

Phase 1 Goes Low: “Latch” Mode

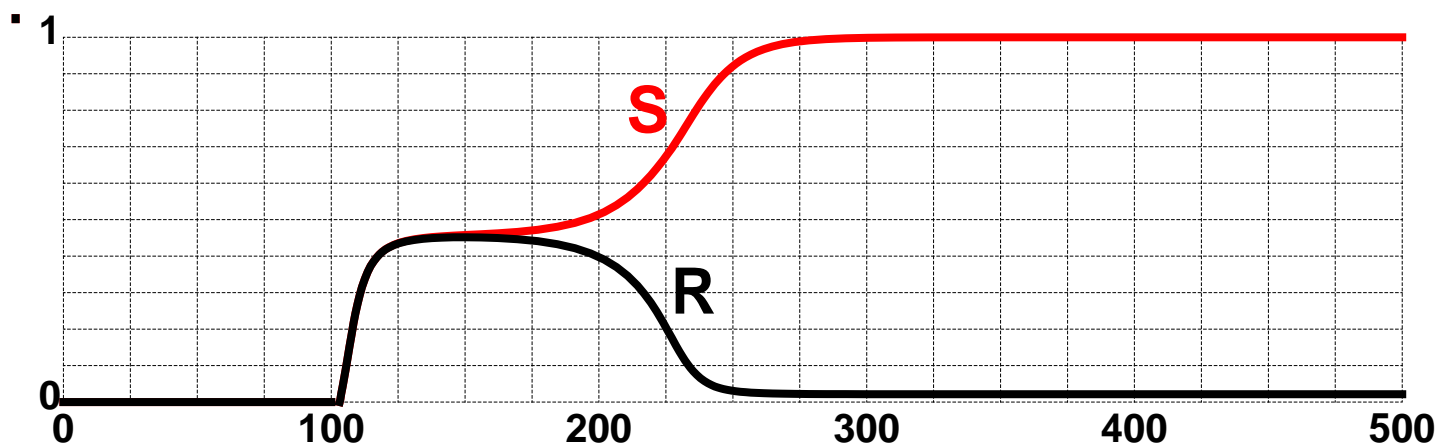
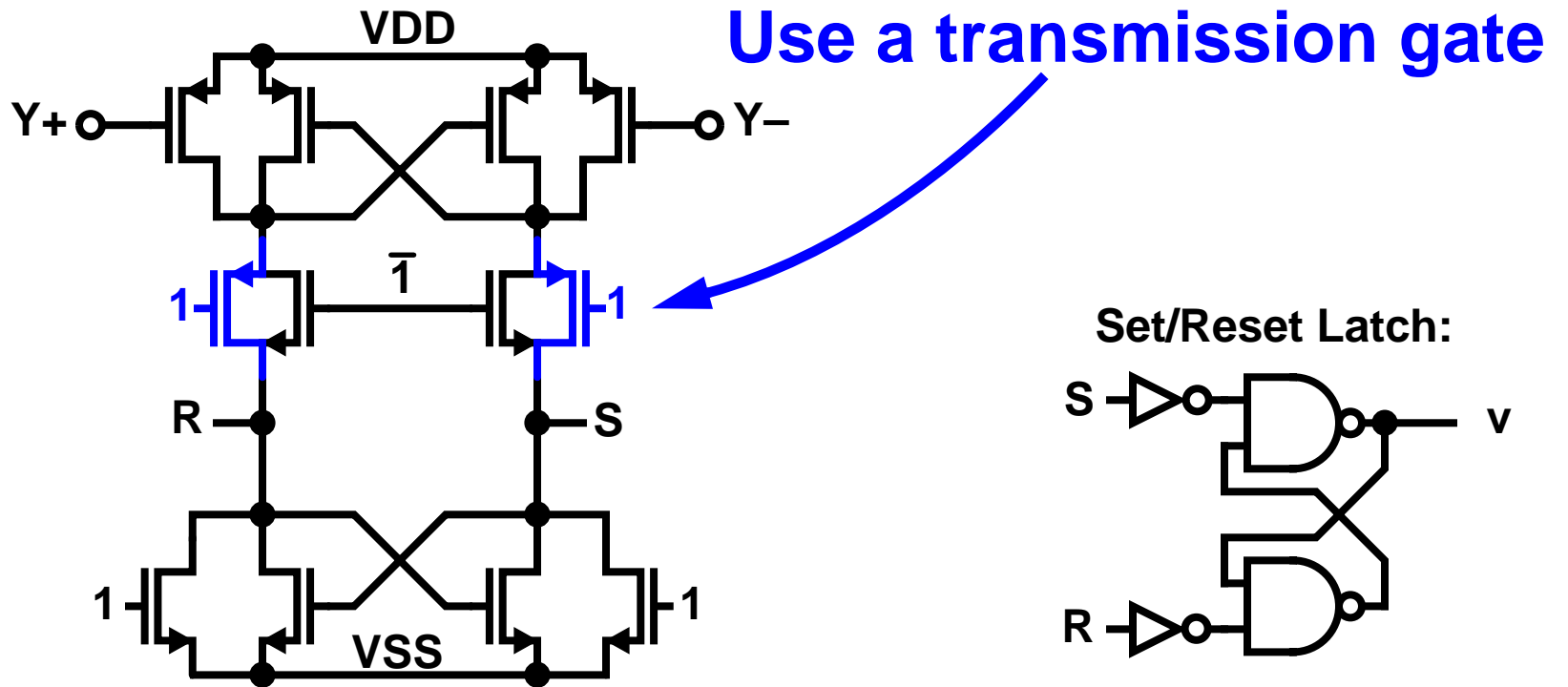


Example Waveforms

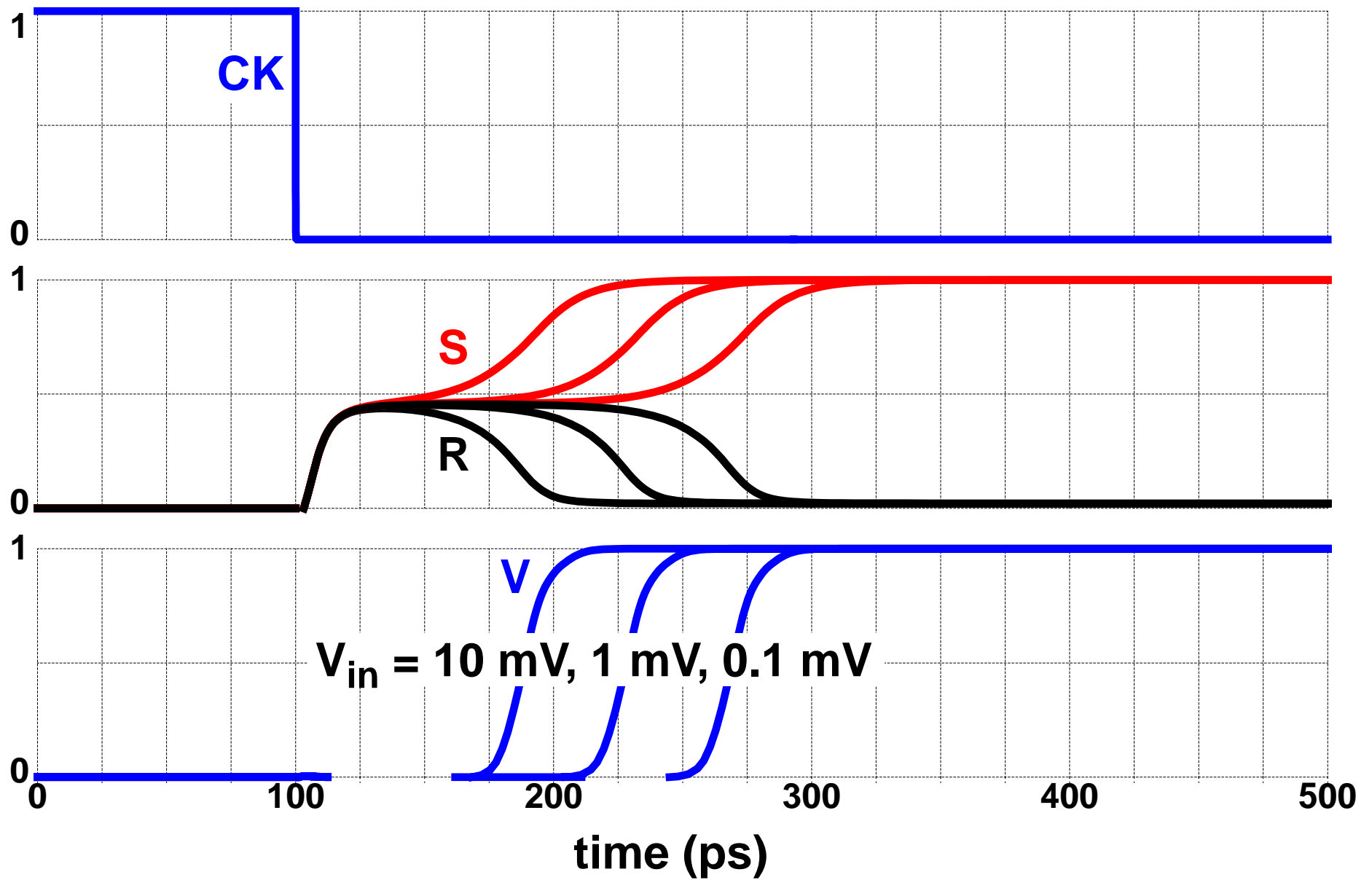
Quick Design in 65nm (VDD = 1V)



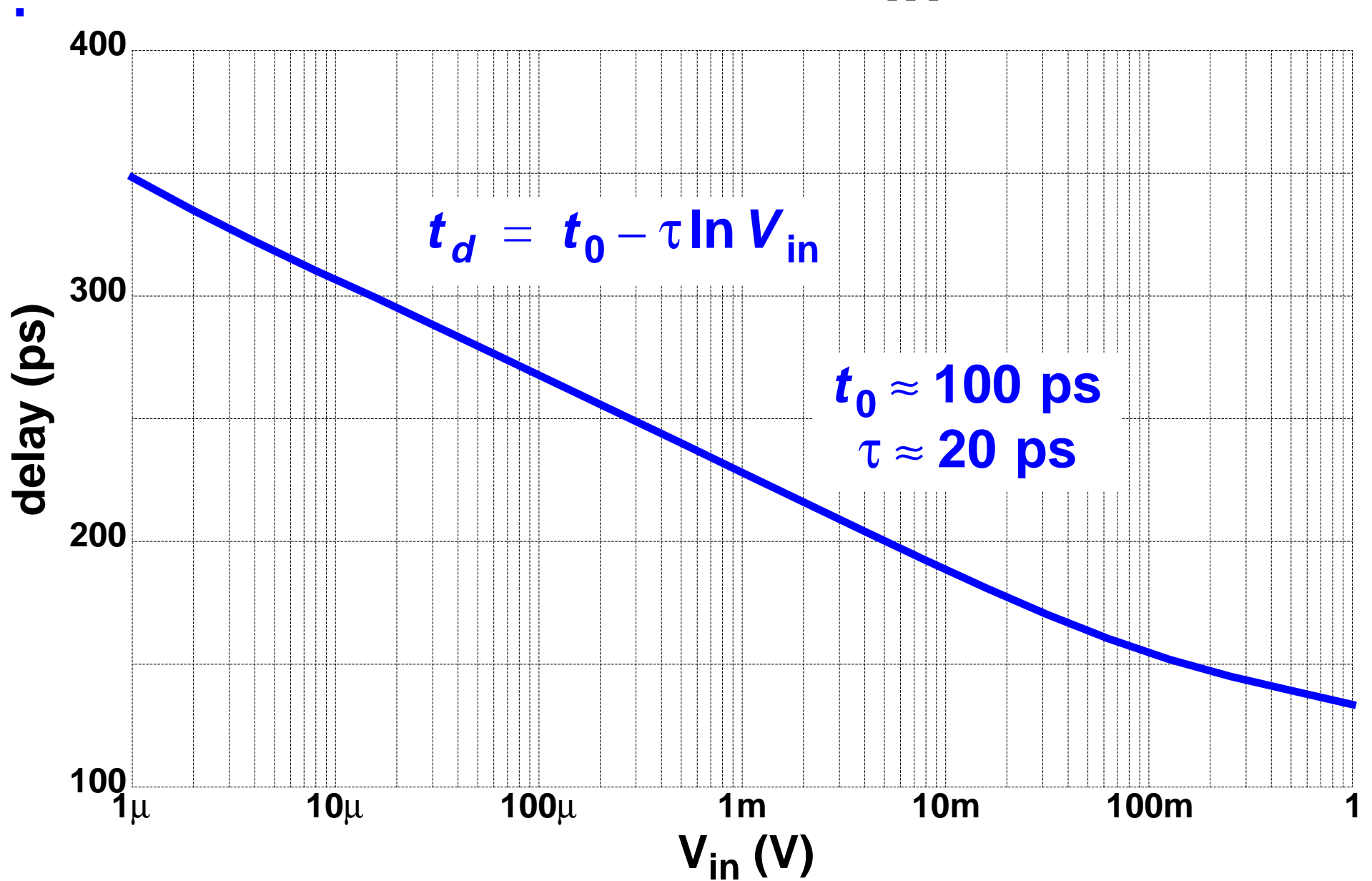
Better Design



Responses for Various V_{in}

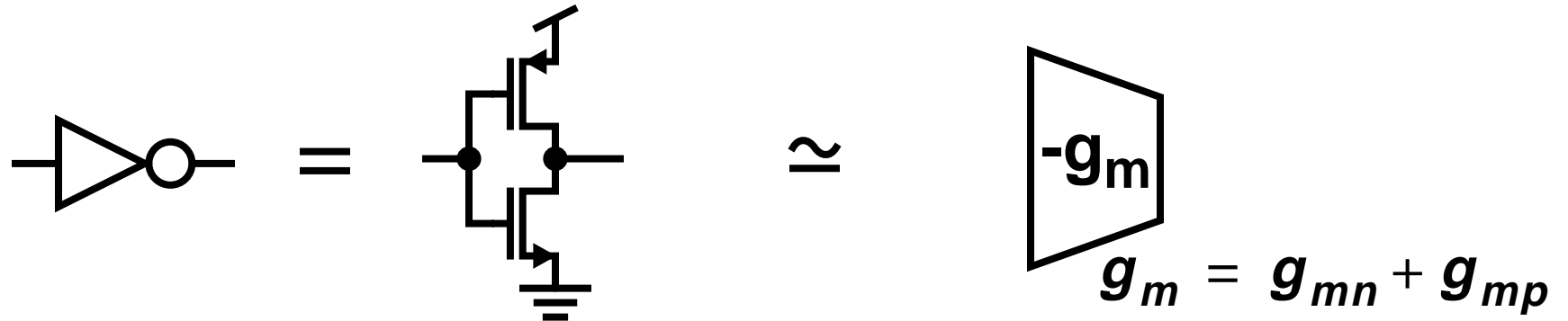


Delay vs. V_{in}

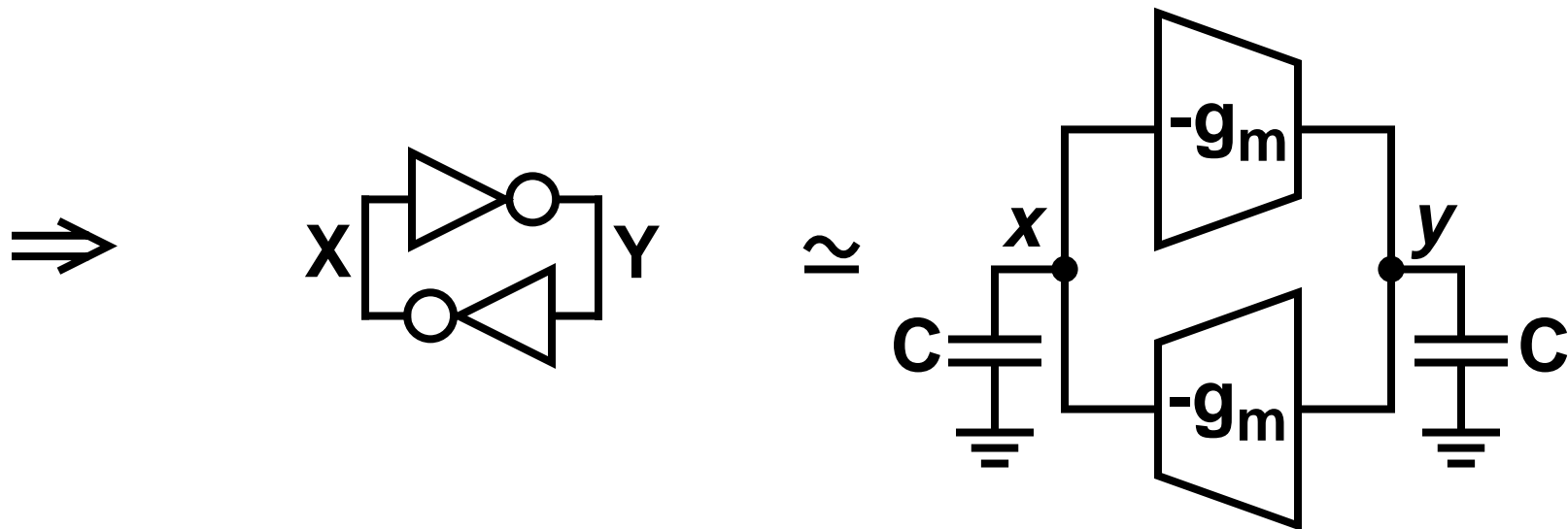


Latch Mode Dynamics

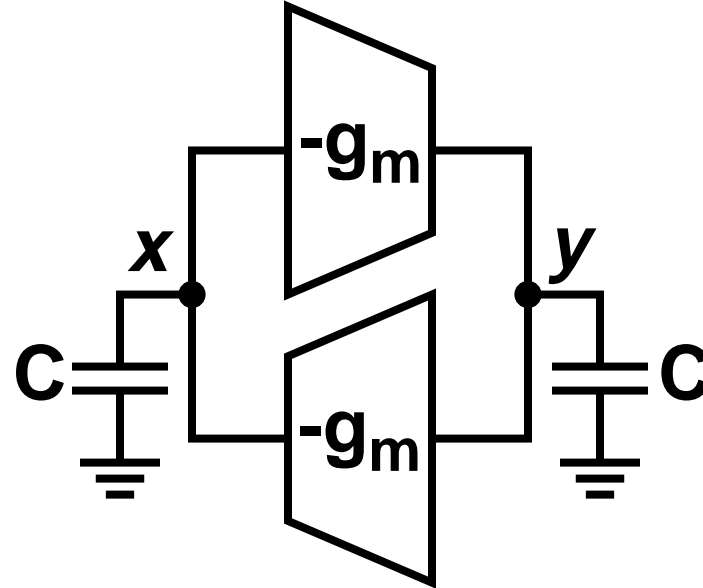
- For V_{in} near the trip point, an inverter is essentially just a transconductor:



- So near balance the comparator looks like this:



Small-Signal Analysis



$$C\dot{x} = -g_m y$$

$$C\dot{y} = -g_m x$$

$$v_d = x - y$$

$$v_{cm} = \frac{x + y}{2}$$

$$C\dot{v}_d = g_m v_d$$

$$v_d(t) = v_{d0} e^{t/\tau}$$

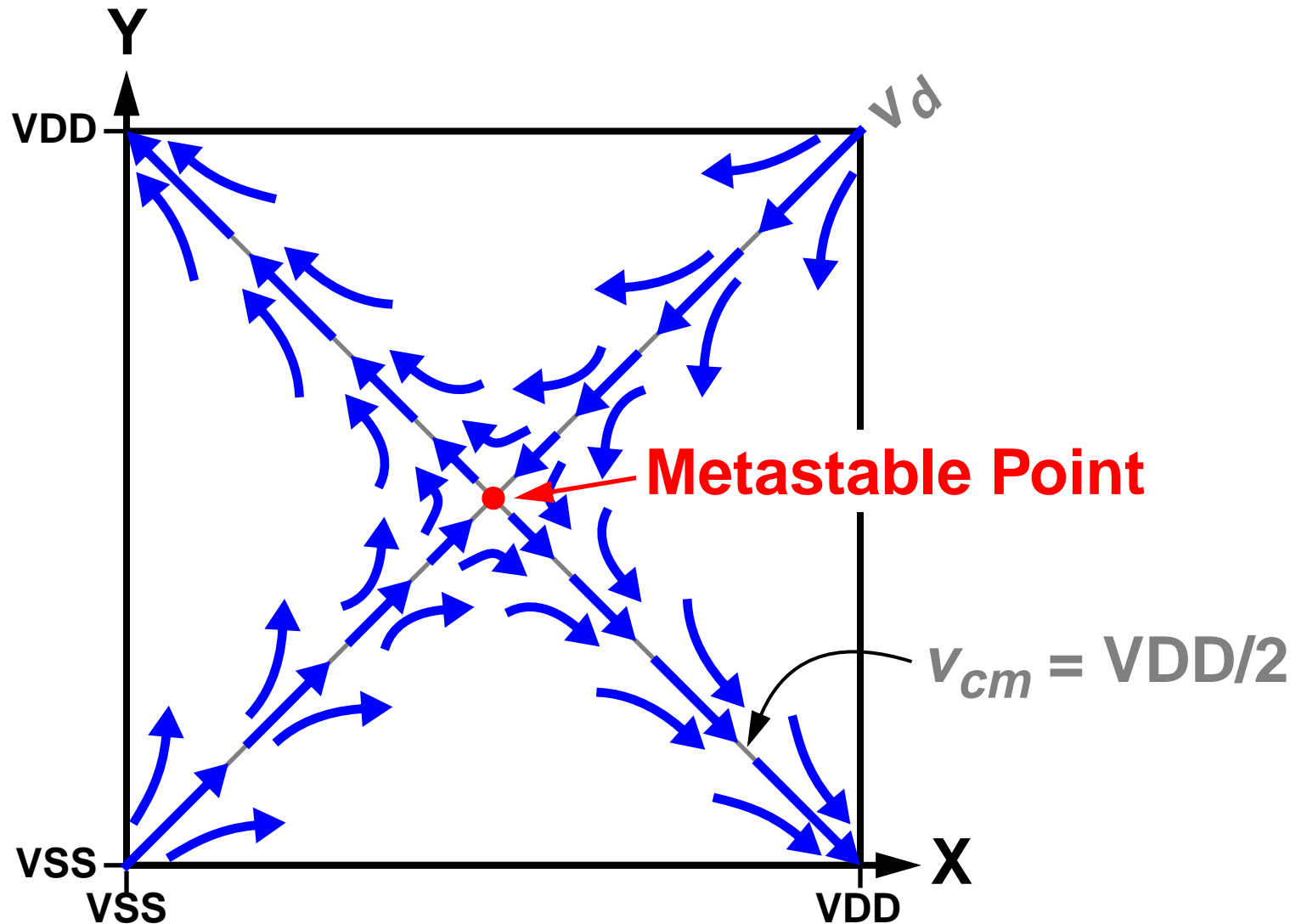
$$C\dot{v}_{cm} = -g_m v_{cm}$$

$$v_{cm}(t) = v_{cm0} e^{-t/\tau}$$

$$\tau = \frac{C}{g_m}$$

- Differential component grows exponentially
- CM component decays exponentially

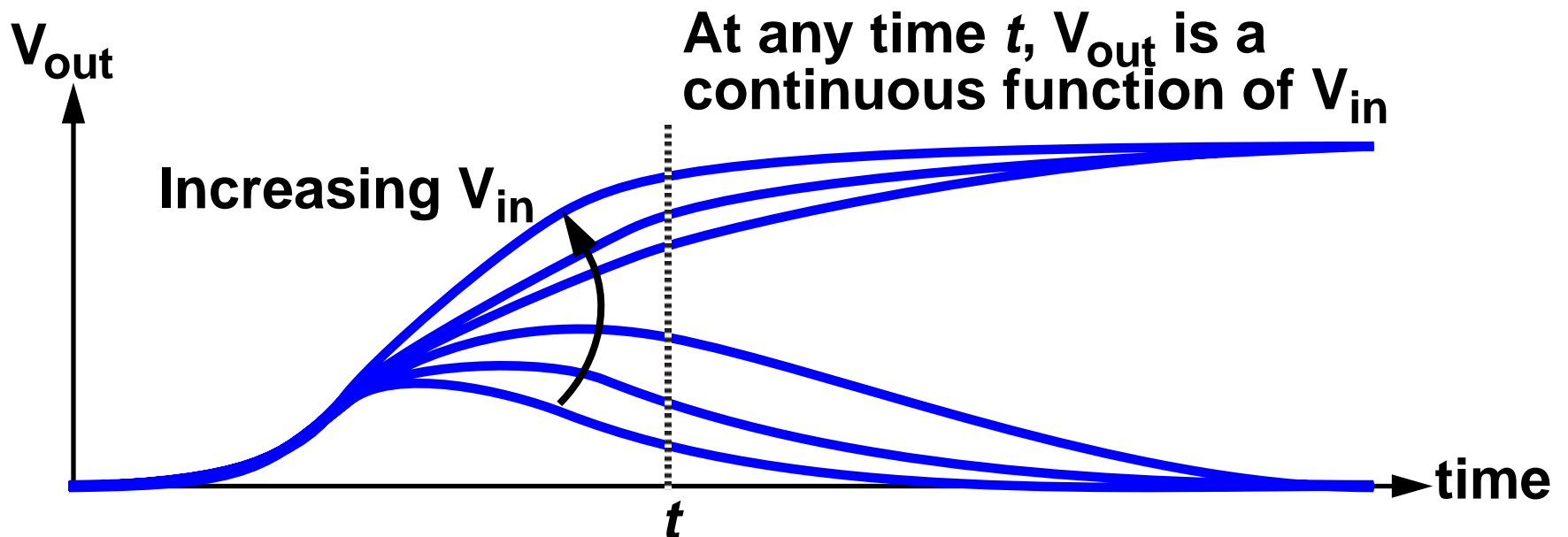
State-Space



- $v_{cm} \rightarrow VDD/2, v_d \rightarrow \pm VDD$

Metastability

- **Metastability is fundamentally unavoidable**
- **Assuming the universe is continuous and deterministic, a comparator can be unresolved for any length of time**



Probability of Error, P_E

$$P_E = P\{\text{not resolved by time } t\}$$
$$= P\left\{V_{in} < \exp\left(-\frac{t - t_0}{\tau}\right)\right\}$$

- Take $t_0 = 100$ ps and $\tau = 20$ ps
- Then for $t = 500$ ps (1 GHz clock with a half-cycle between the comparator's clock and the clock of the subsequent latch),

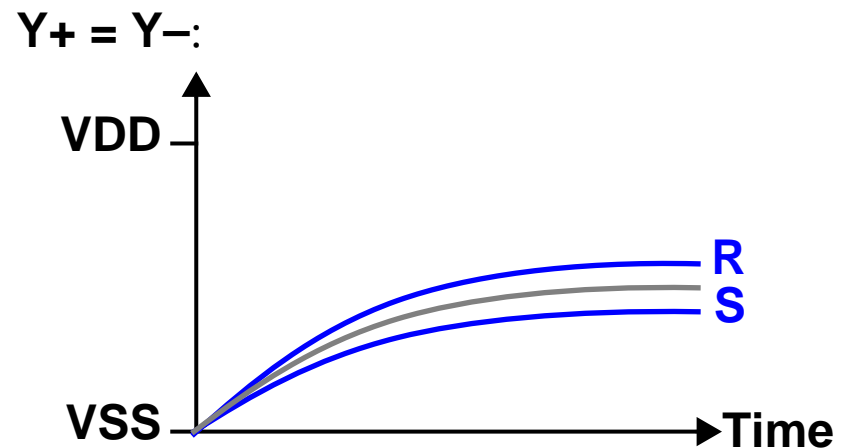
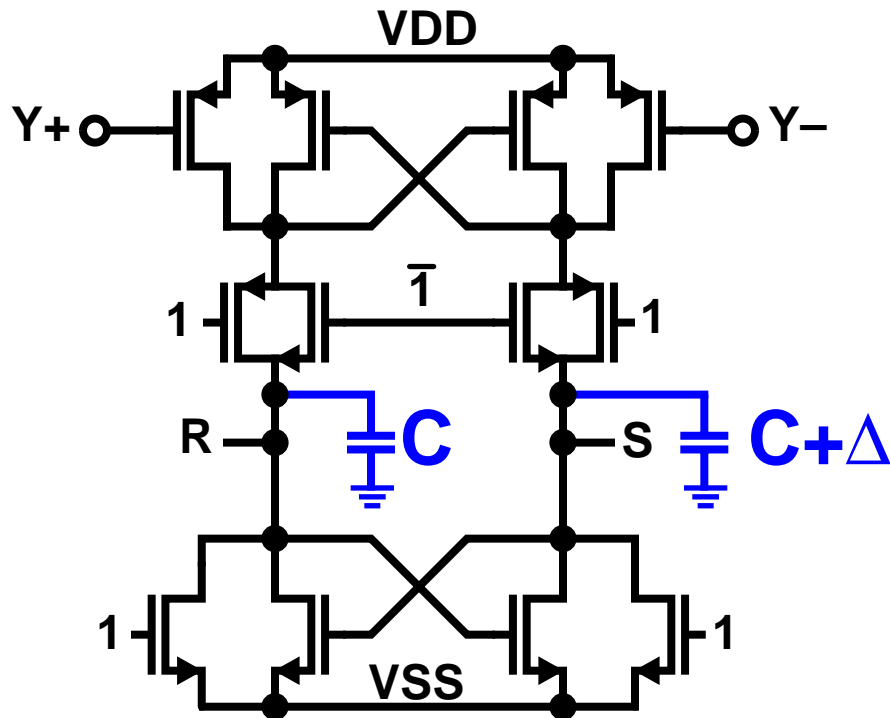
$$P_E = P\{|V_{in}| < 2 \text{ nV}\}$$

- Assuming V_{in} is uniformly distributed in $[-0.5, +0.5]$ V, $P_E = 2 \times 10^{-9}$
Metastability occurs twice a second!

Metastability Summary

- **Metastability is unavoidable**
All you can do is make τ small and give enough time for regeneration to make P_E small.
- **Supplementary Slides examine the effects of quantized charge and noise**
Noise helps a comparator resolve when $V_{in} = 0$ but usually does not reduce P_E
- **At best, metastability causes SNR degradation**
At worst, it causes a system failure.

Dynamic Offset

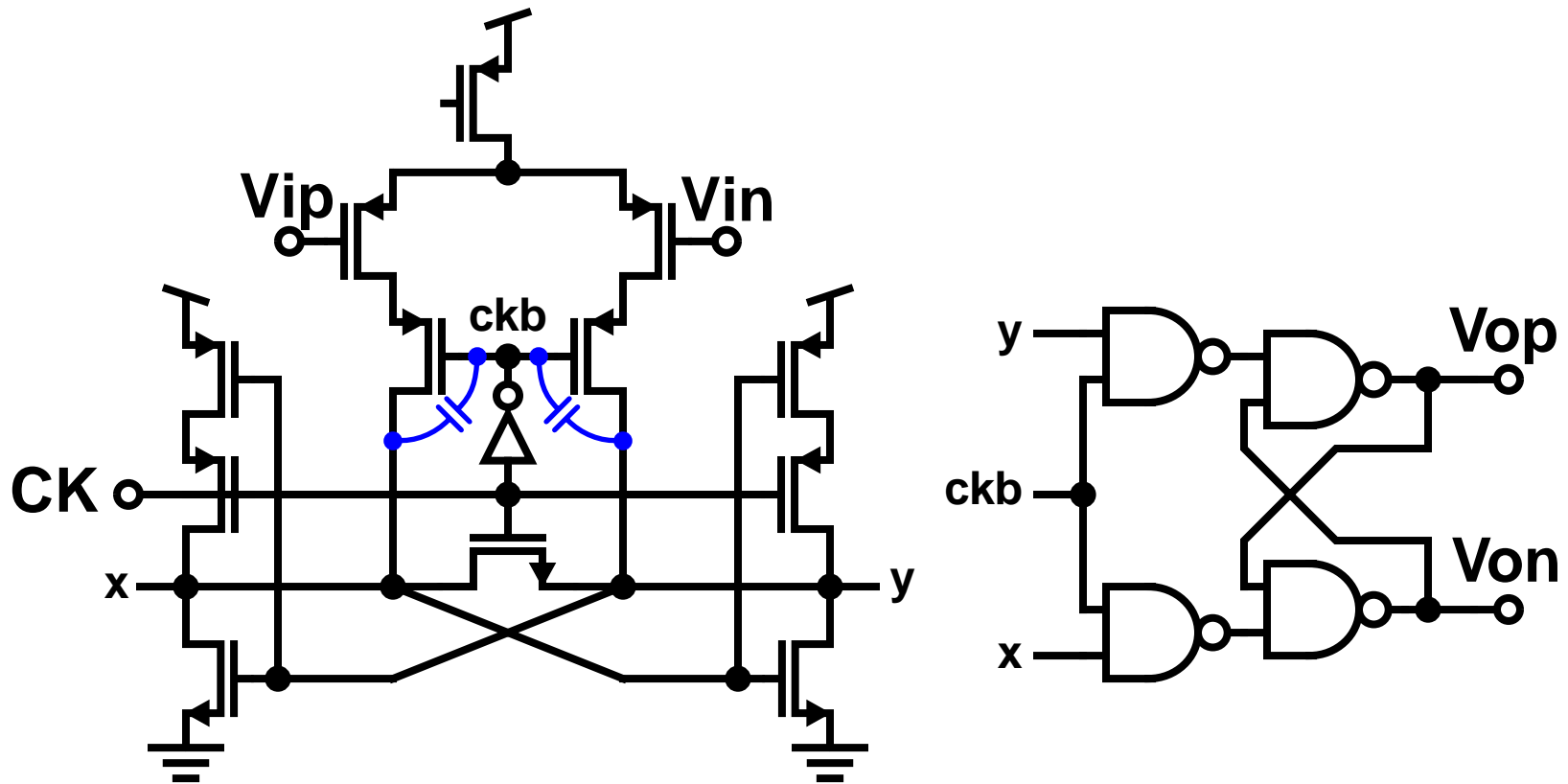


**S rises more slowly than R
⇒ offset**

- **Mismatched parasitic capacitance also causes offset**
20 mV/fF for this comparator!
- **Bad design– Can fix this!**

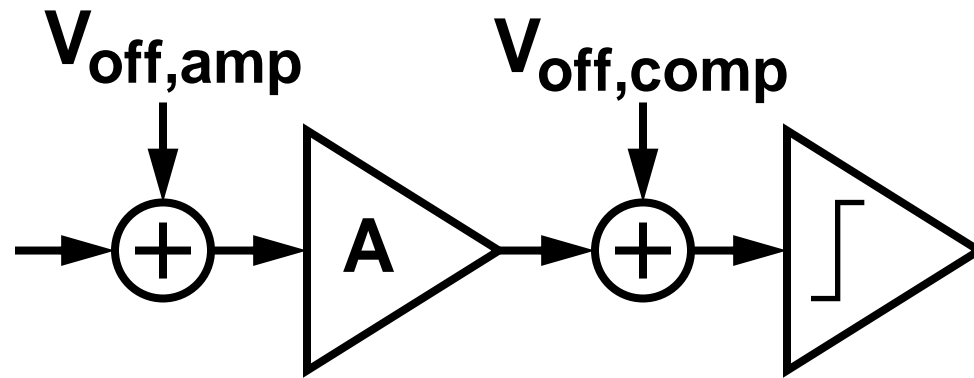
Improved Comparator

[S&T Fig. 9.36]



- **Reset when $CK = 1$; regenerates when $CK = 0$**
- **x & y don't step if biased properly**
Mismatch in overlap capacitance still a problem.

Reducing Offset with a Preamp

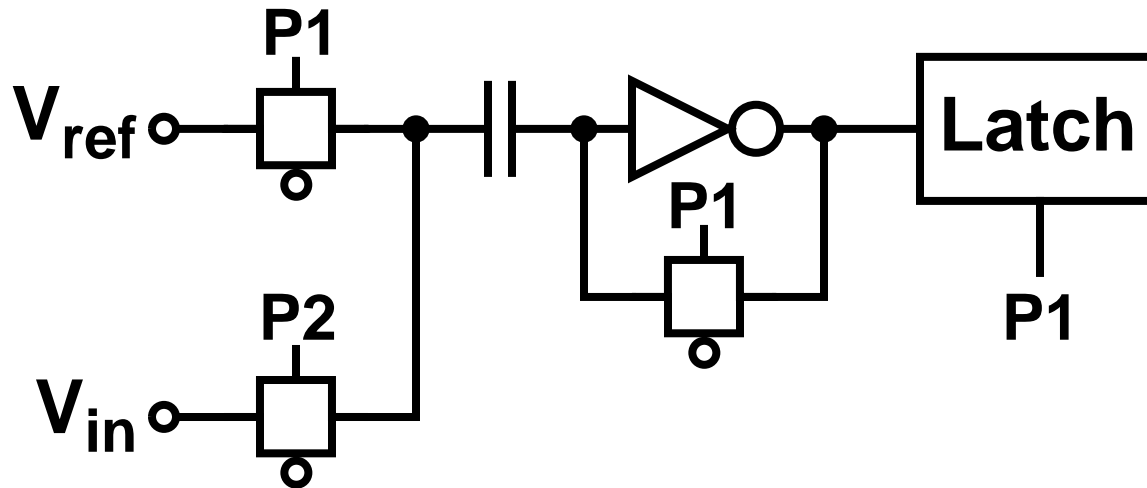


$$V_{\text{off,tot}} = V_{\text{off,amp}} + V_{\text{off,comp}} / A$$

- + **Comparator offset is reduced by preamp gain**
Amplifier offset dominates.
- + **Amplifier also isolates driving stage from “charge kickback”**
- **Amplifier bandwidth limits speed, especially recovery from overload**

Auto-zeroed SC Comparator

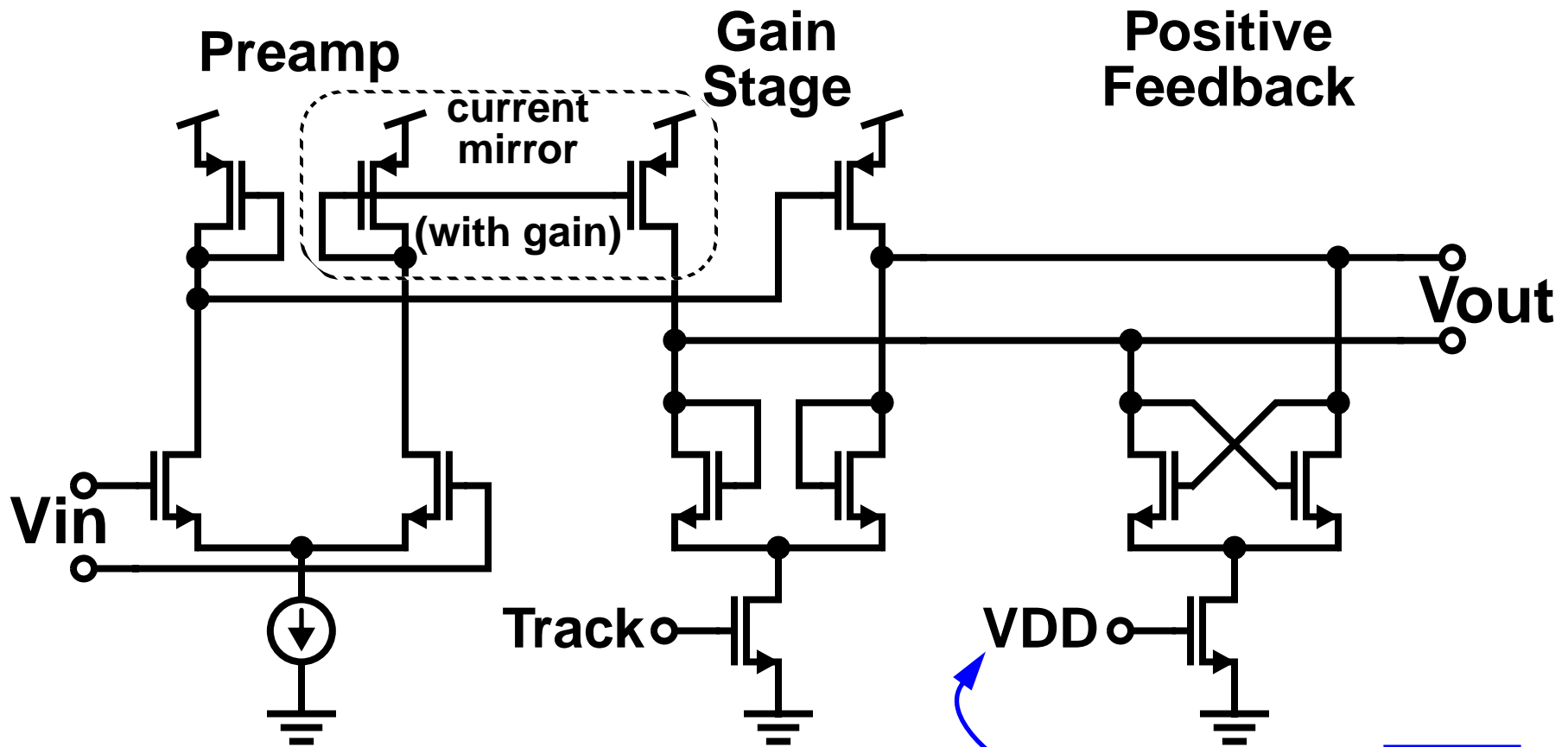
[J&M Fig 13.17]



- During P1, the inverter/amplifier is biased at its threshold/offset voltage
- During P2, the difference between V_{in} and V_{ref} is amplified

Comparator with Preamp

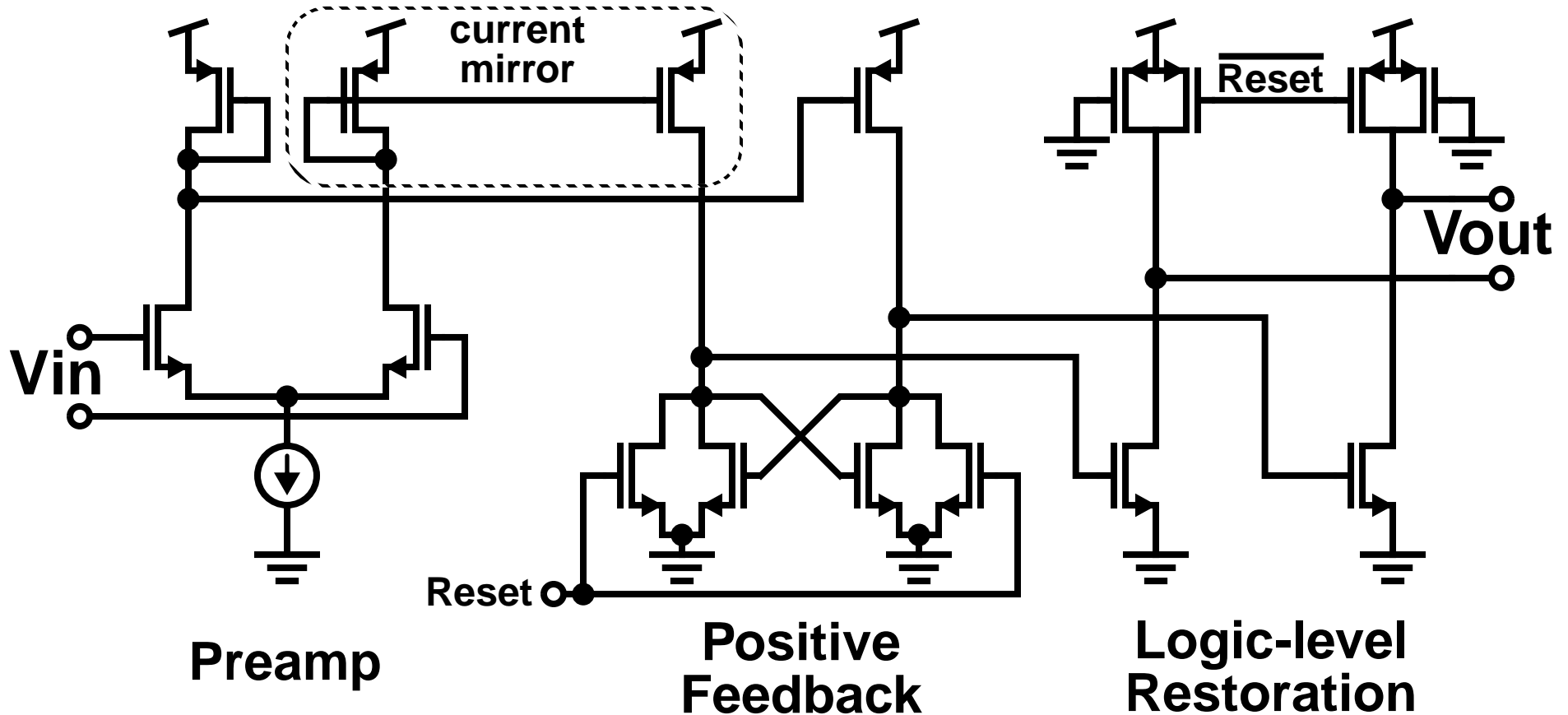
[J&M Fig. 7.16]



Better to use Track to minimize dynamic offset

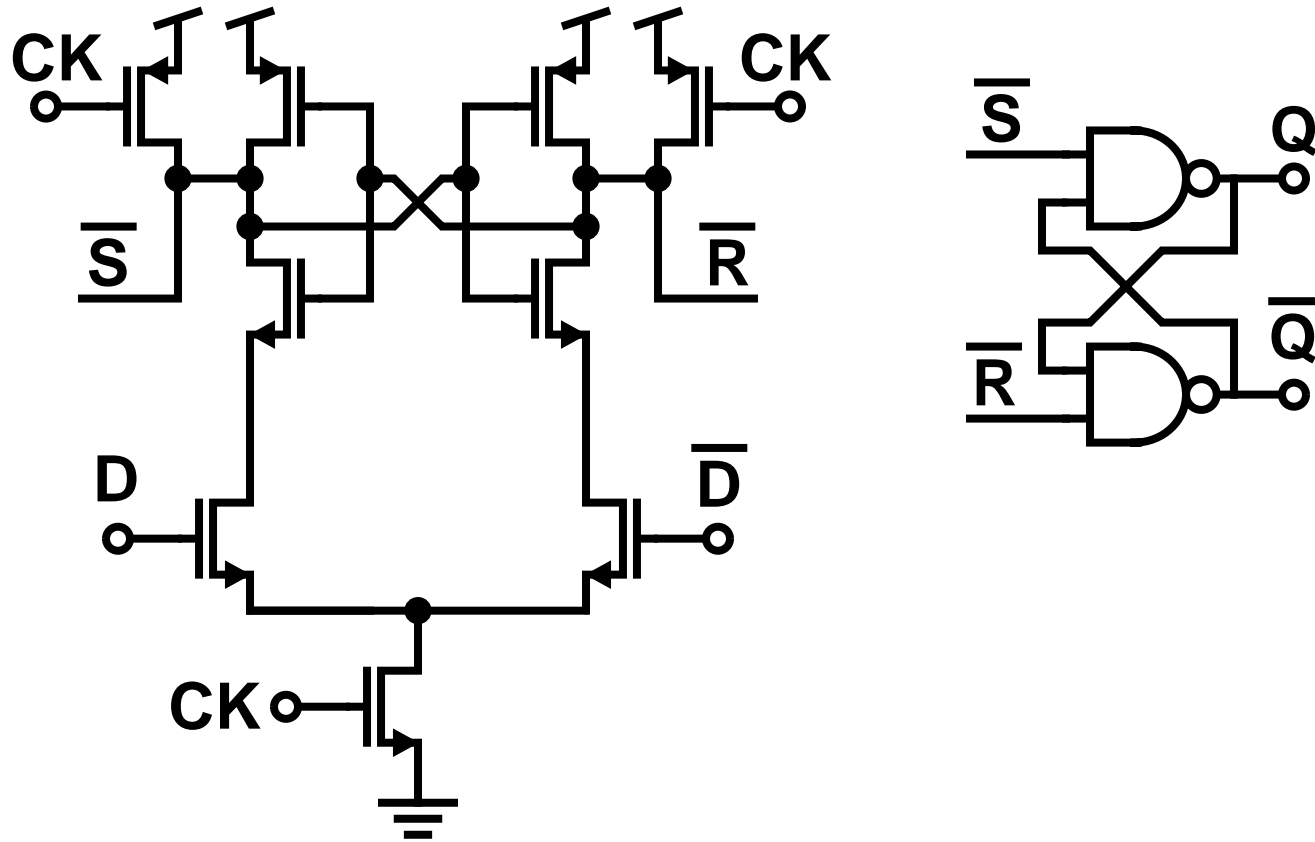
Two-Stage Comparator

[J&M Fig 7.17]



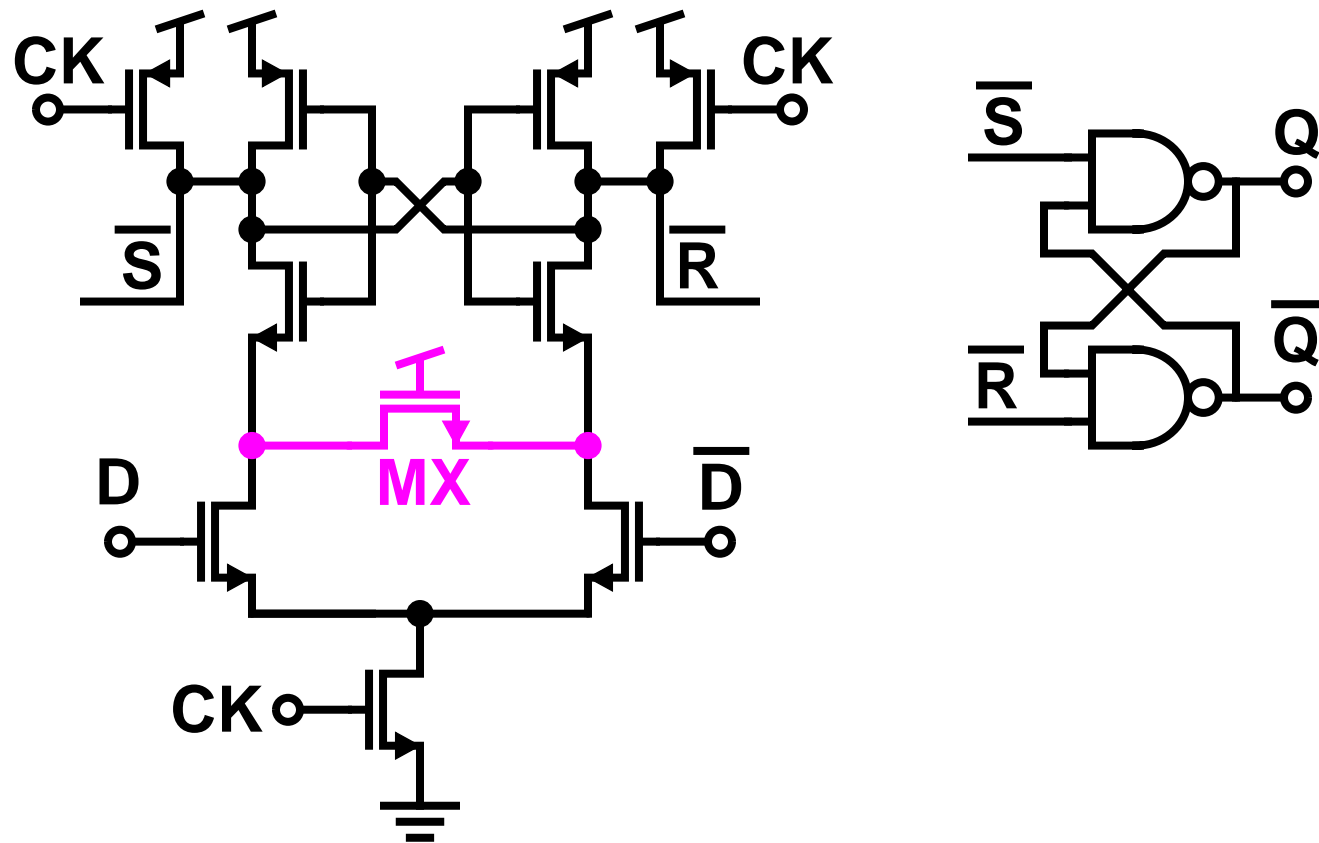
- Precharges regeneration nodes low & digital output nodes high

StrongArm Flip Flop



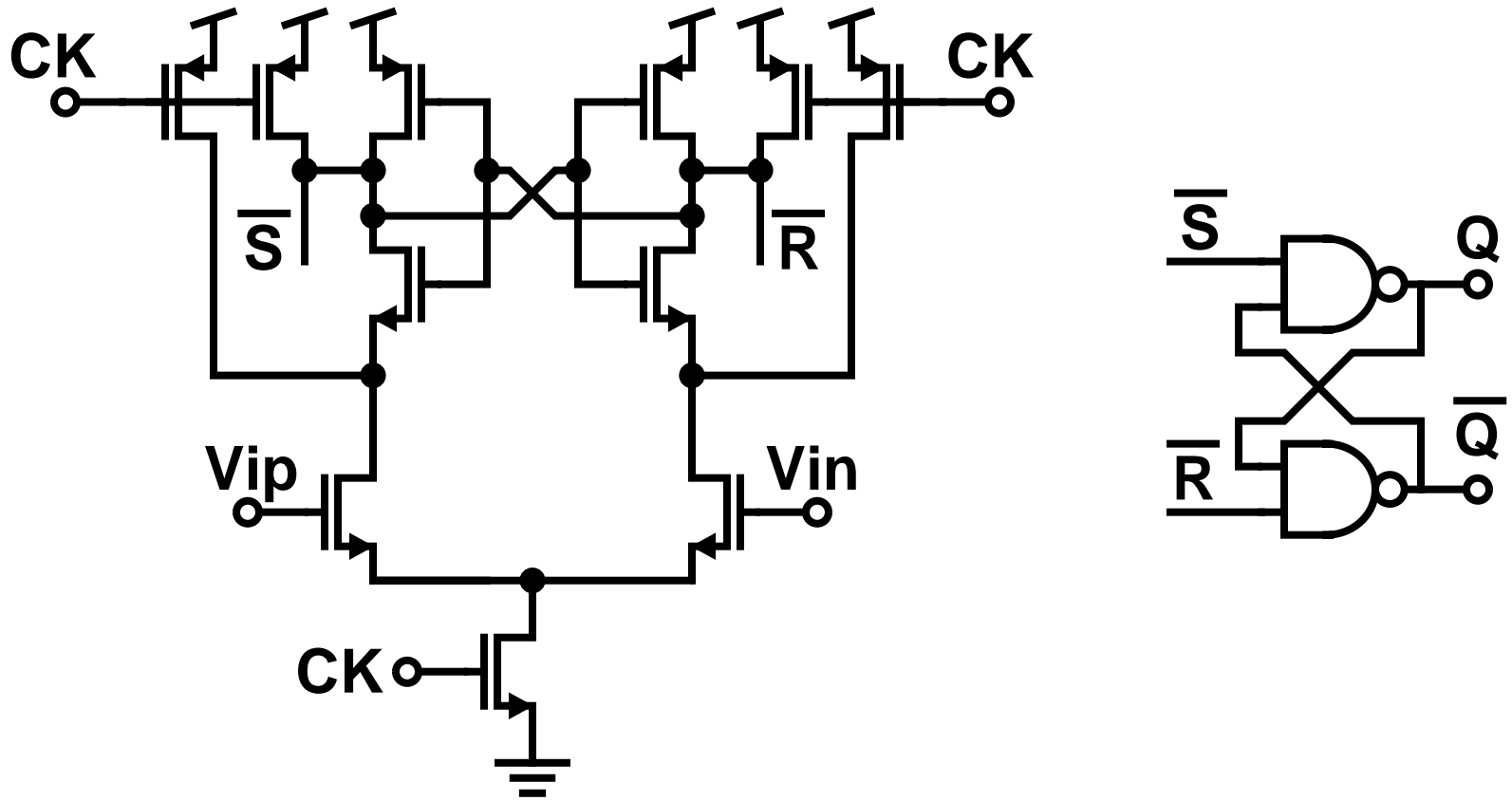
- + No static current
 - + Can be used as a comparator
- Note that input CM voltage defines the bias point during regeneration.

Improved StrongArm Design



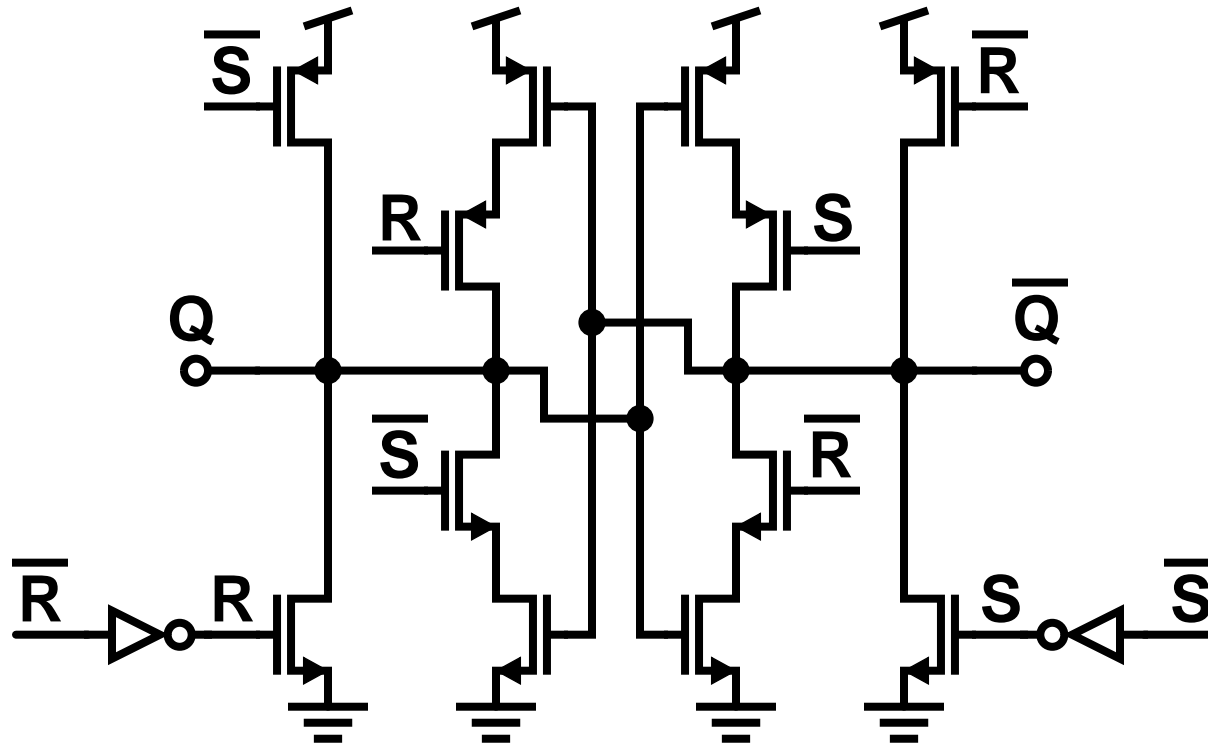
- **MX provides DC path to ground for leakage currents in case D changes after CK goes high**
MX is needed to make latch static.

Alternative Arrangement



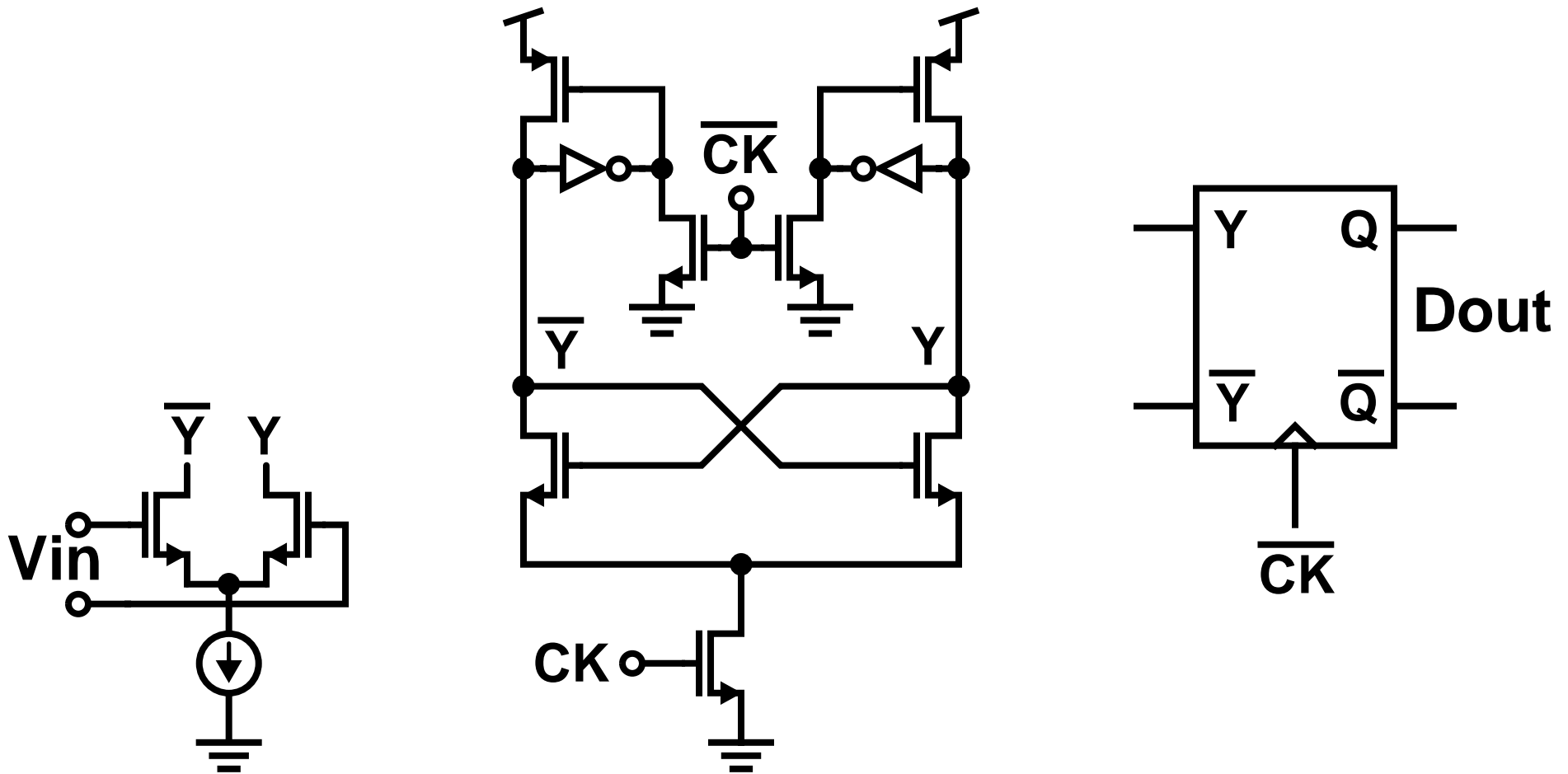
- **Well-defined initial state \Rightarrow less hysteresis**
[Abidi 2014CICC] “Understanding the Regenerative Comparator Circuit”

Symmetric Latch



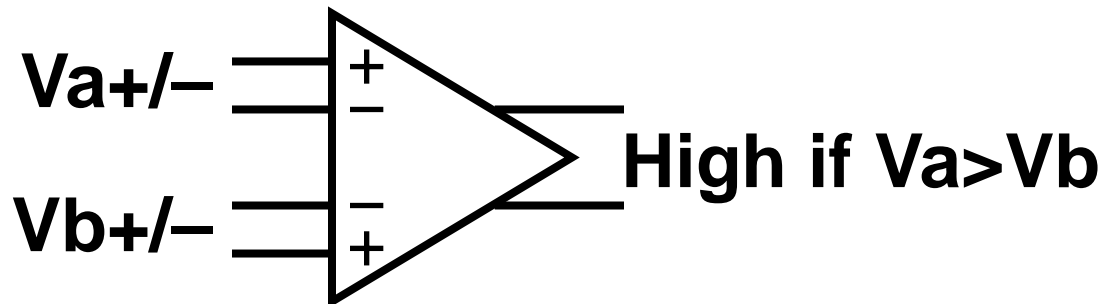
- **Faster than cross-coupled NAND gates**

Yang's High-Speed Comparator

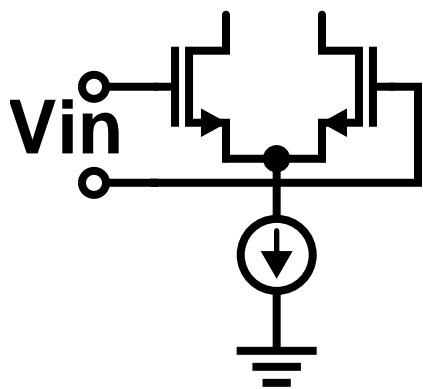


- $\tau_{nom} = 6 \text{ ps (!)}$ in 65nm CMOS
Used in a $CT\Delta\Sigma$ ADC clocked at 4 GHz [Shibata2012].

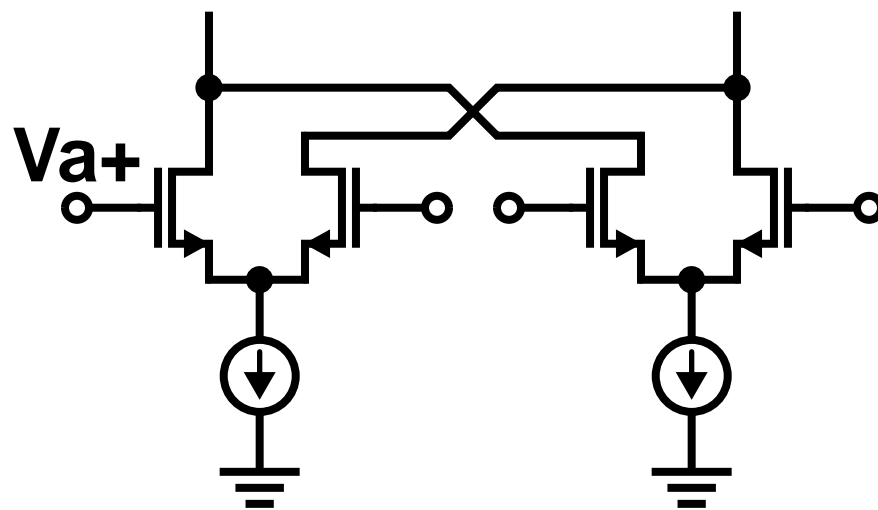
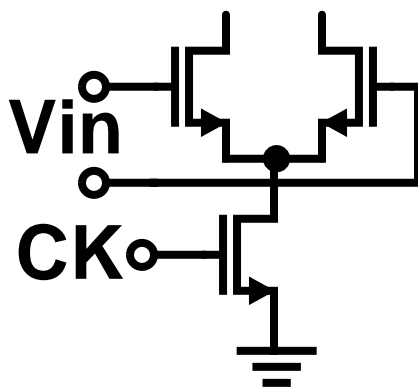
Dual-Difference Comparator



In any of our comparator circuits,
replace:

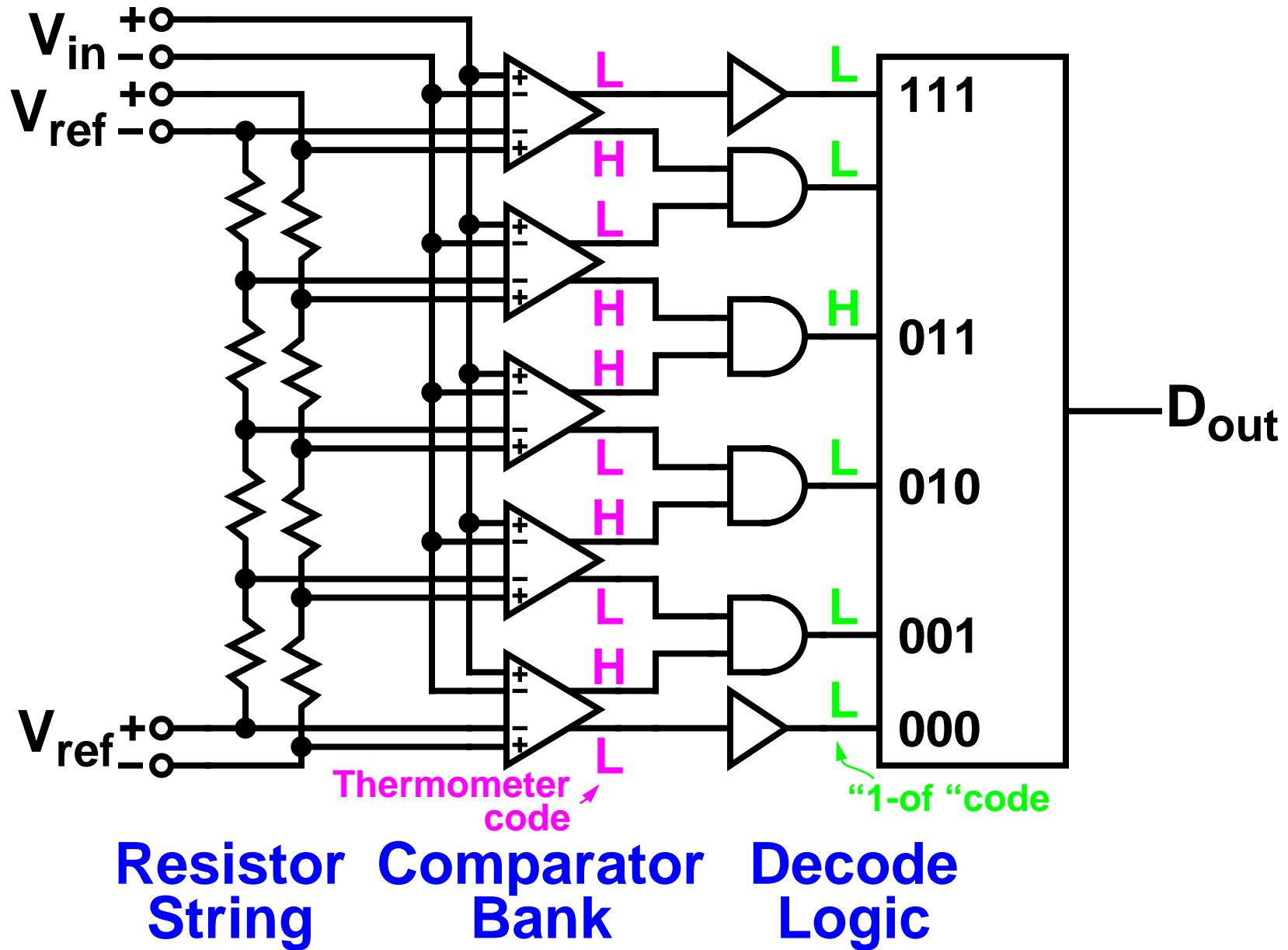


or

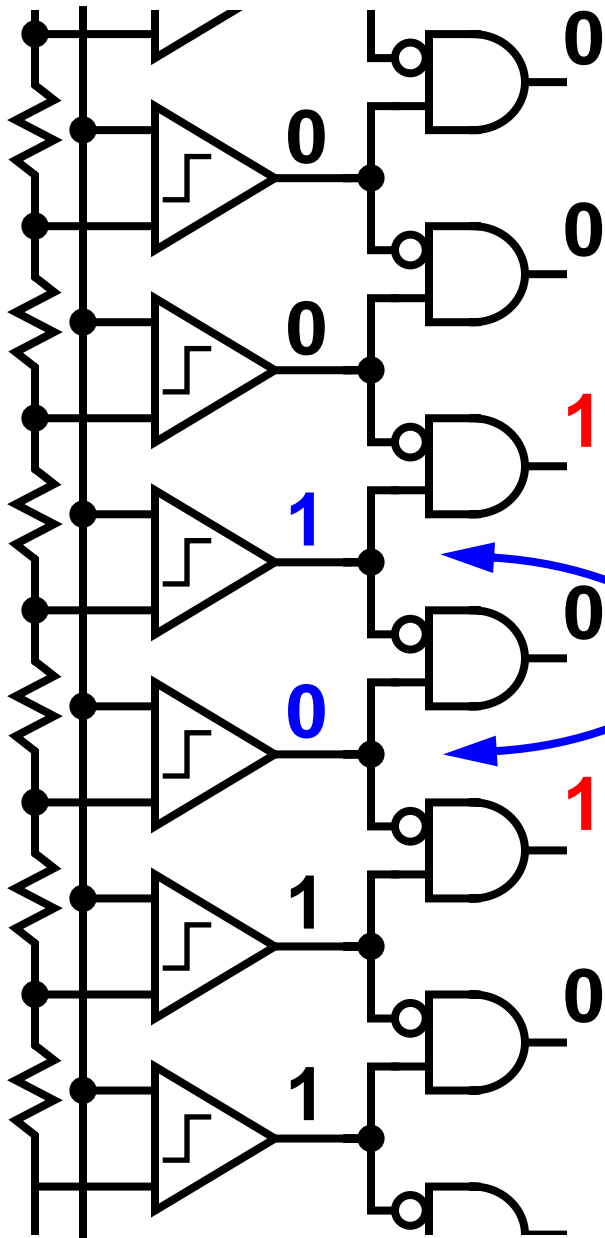


Q: Where should V_{a-} go?

Flash ADC



Flash Bubbles



- Need to modify logic to handle bubbles gracefully unless bubbles guaranteed to not occur

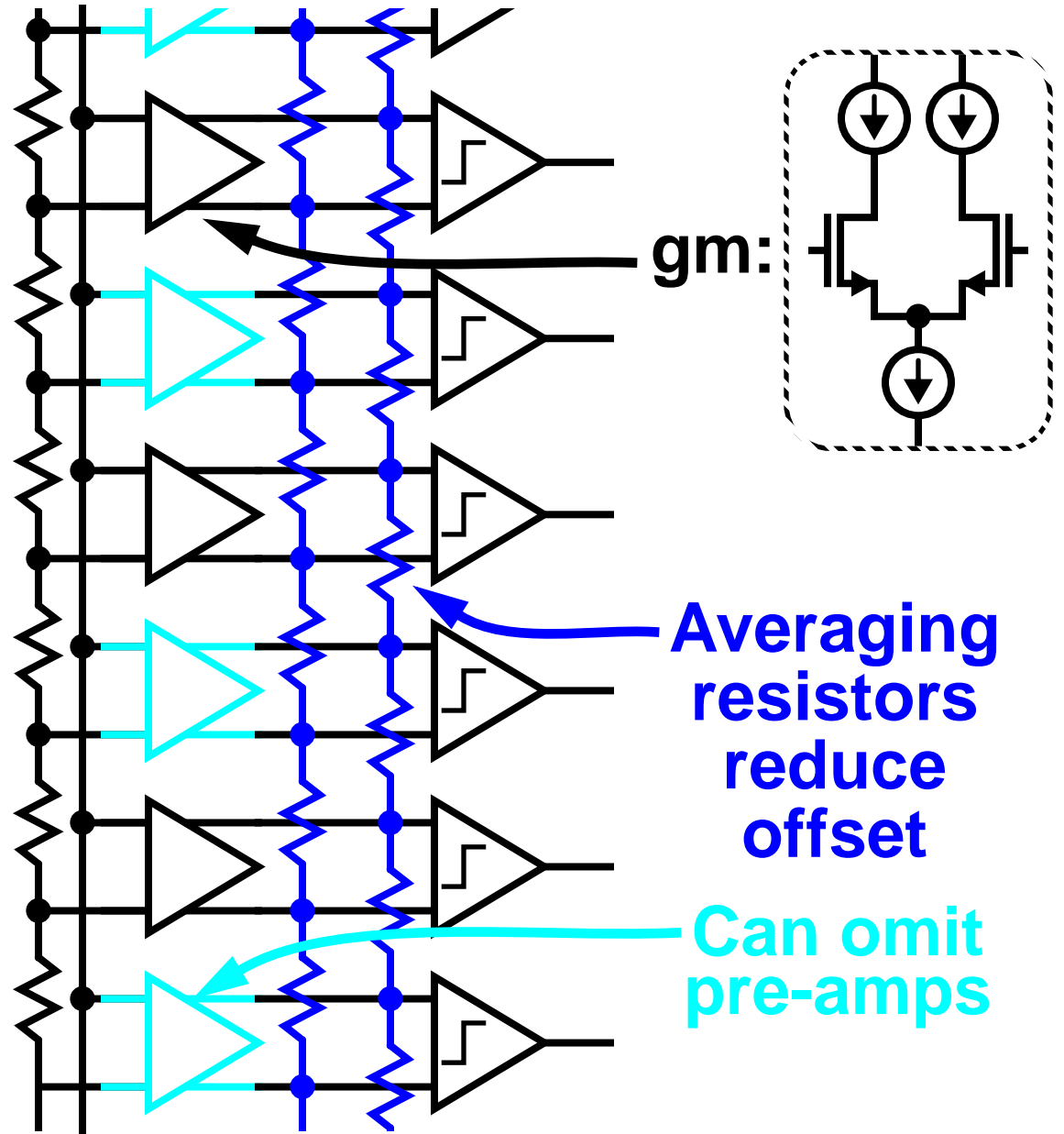
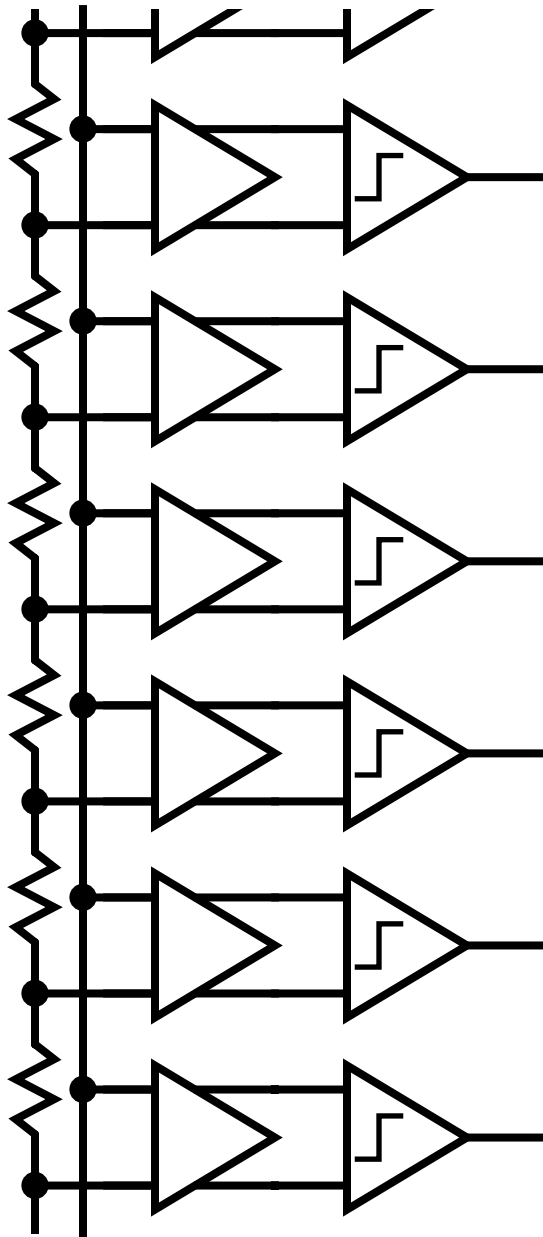
**Flash
Bubble**

**Code
Violation**

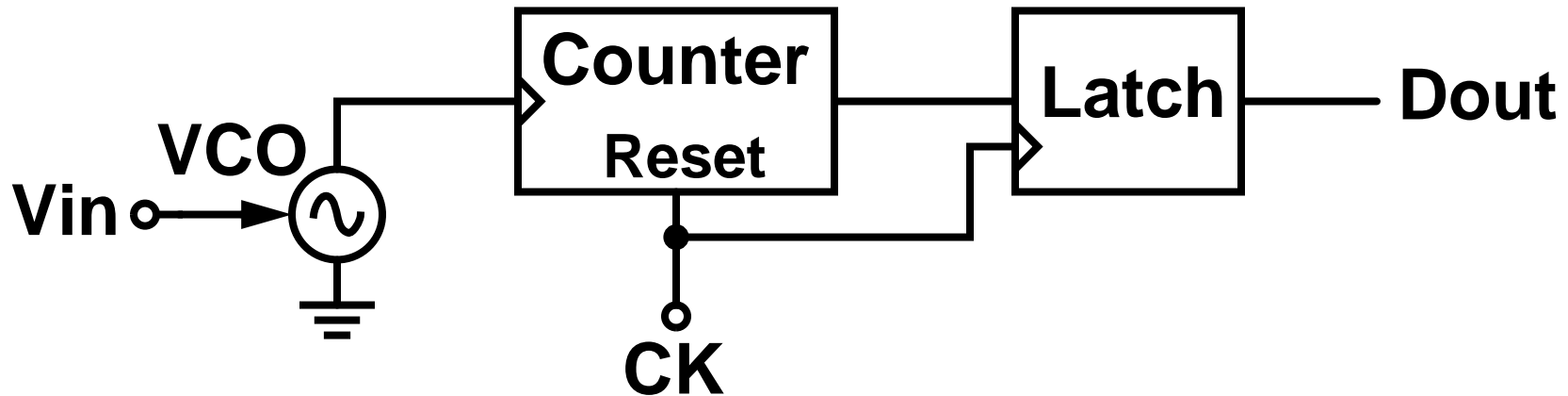
- Counting the number of 1s is the safest method

Use a “Wallace-Tree Adder”

Averaging and Interpolation

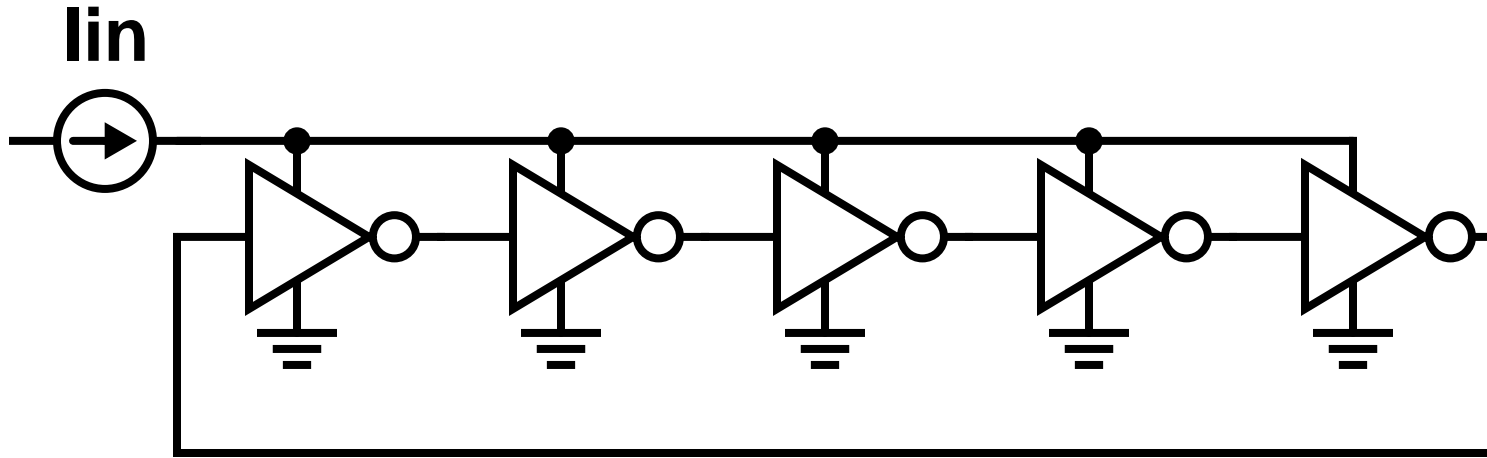


VCO as a Quantizer— Concept



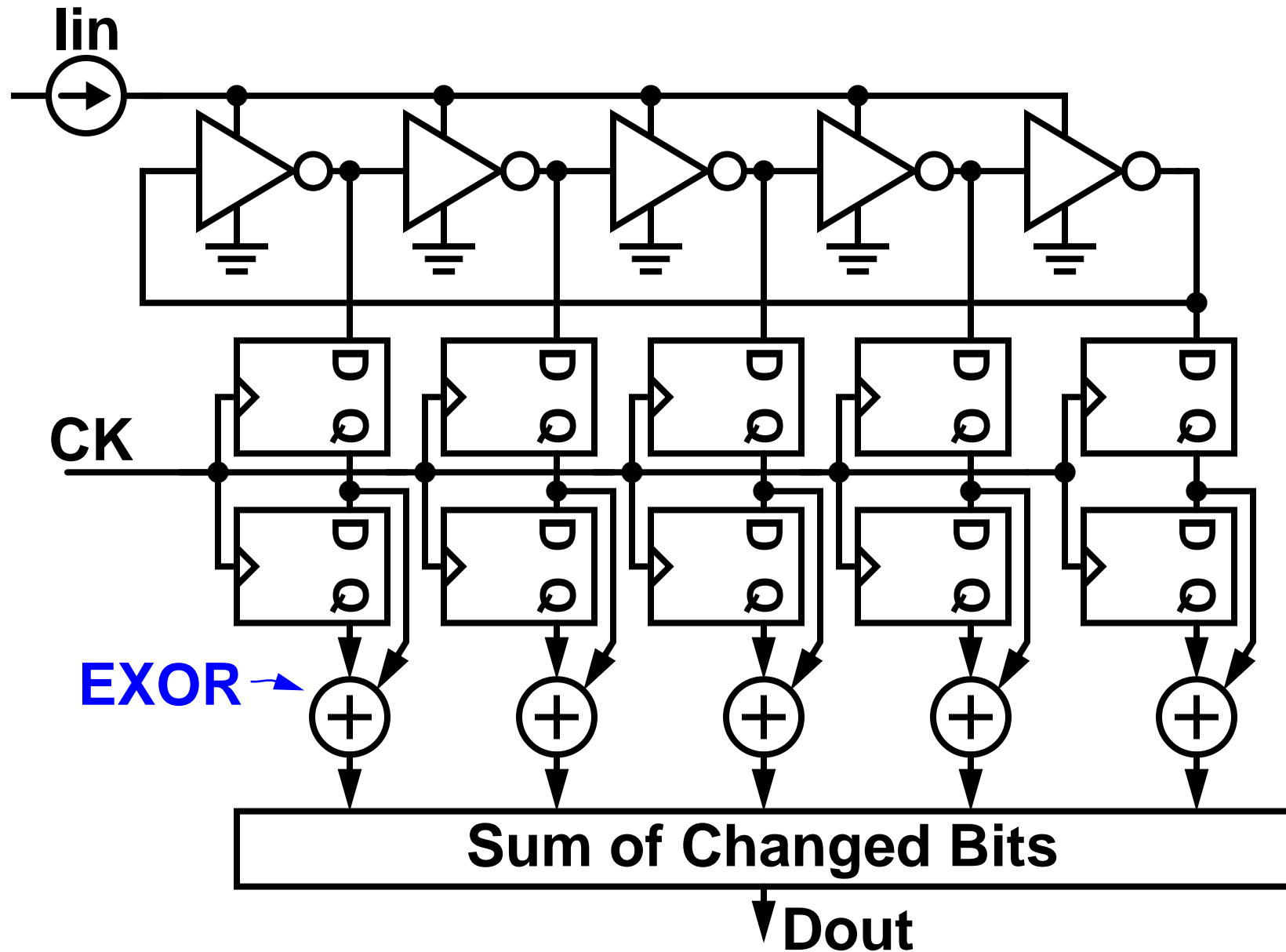
- + Simple
- + Monotonic
- Not linear
- Ill-defined full-scale

Current-Controlled Ring Oscillator (CCRO)



- **Oscillation frequency is proportional to current**
- ⇒ **Can make a fairly linear quantizer**

CCRO + Phase latch + EXOR = Q!

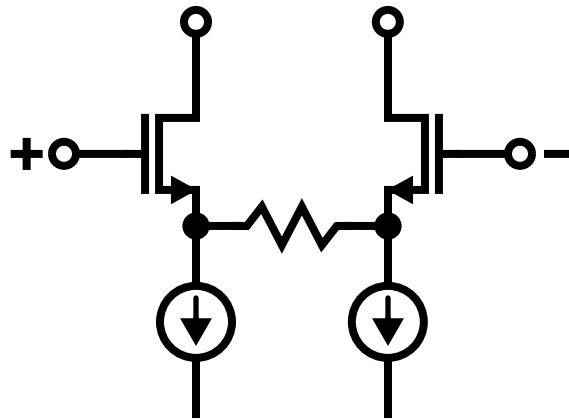


Improvements to CCRO Quantizer

- **Put EXOR before 1st FF and remove 2nd FF**
To eliminate unnecessary delay.
- **Add inverters to increase resolution**
Must keep f_{osc} constant to maintain full-scale.
- **Use 2 rings in a pseudo-differential arrangement**
To cancel even-order distortion and make mid-scale self-referenced.
- **Use multiple rings with phase interpolation to increase resolution without hitting f_{osc} ceiling**
- **Driving the elements of the DACs with the EXOR outputs directly results in *mismatch-shaping***

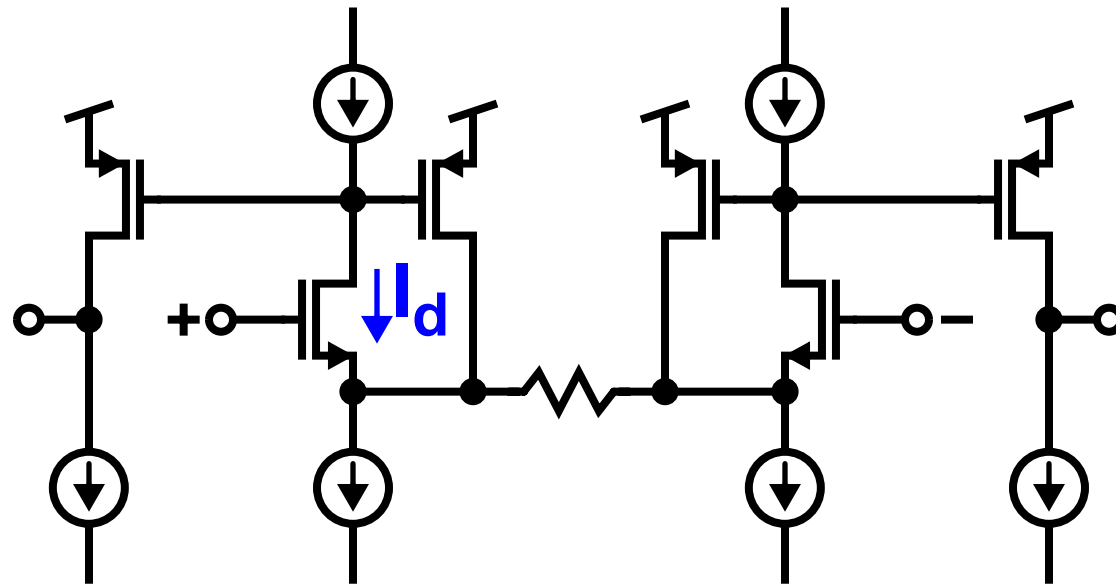
NLCOTD: Linear Transconductors

Degenerated Differential Pair



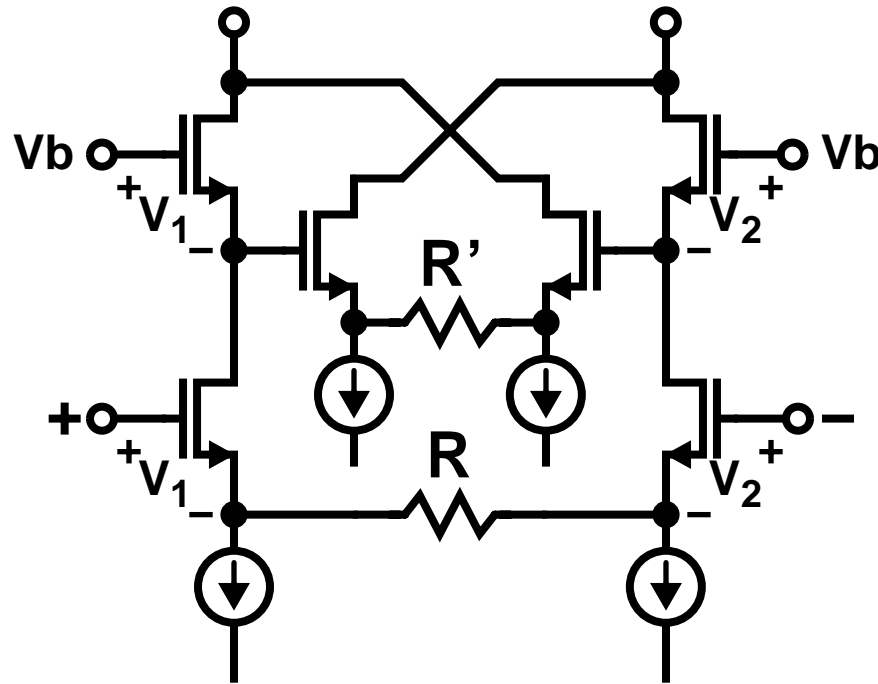
- + Simple!
- V_{gs} varies nonlinearly with $I_{out} \Rightarrow g_m$ is nonlinear

Force Constant V_{gs}



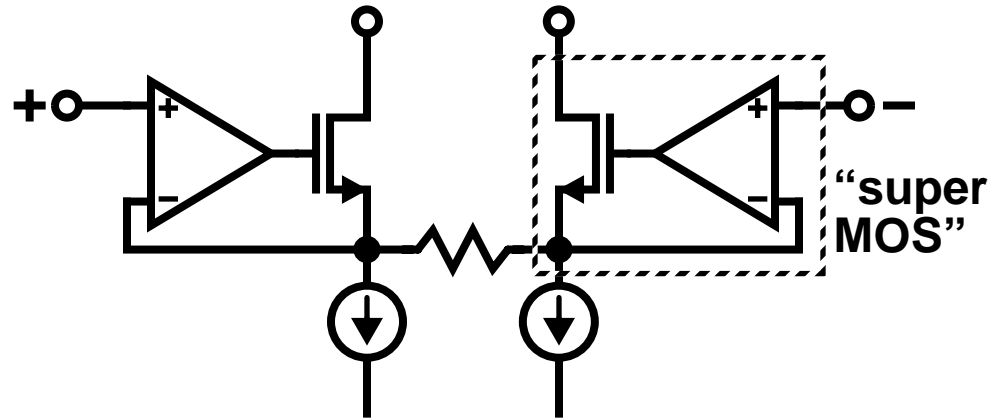
- I_d constant $\Rightarrow V_{gs}$ constant
- Linearity dependent on current-mirror linearity

Cascomp



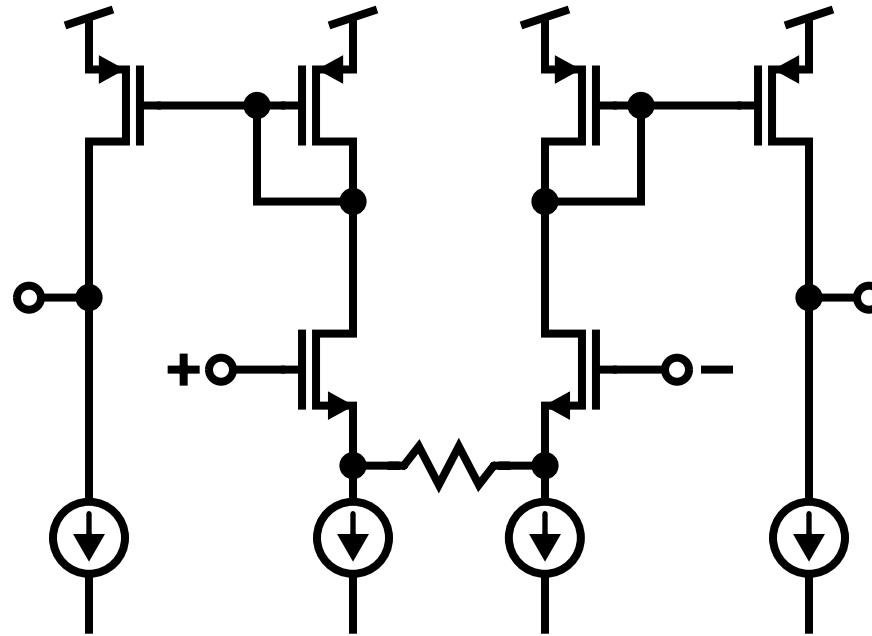
- V_{gs} of input devices replicated in cascodes and distortion-cancelling current injected into output
- + All NMOS \Rightarrow fast
- Cancellation depends on matching
Should tie bulk to source?

Add Op Amps



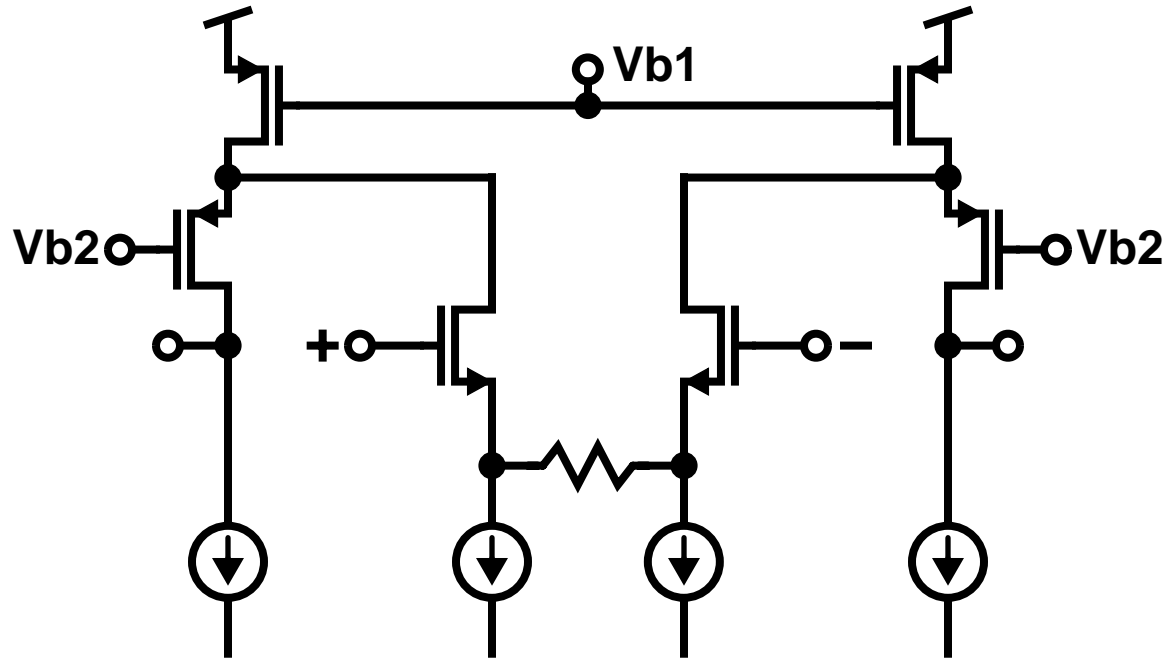
- + Linearity limited only by op amp gain and BW
- + High output resistance
- Output compliance depends on input swing

Mirror the Output Current



- + Output compliance is $V_{DD} - 2 V_{dsat}$
- Top of differential pair at $V_{DD} - V_{gs}$

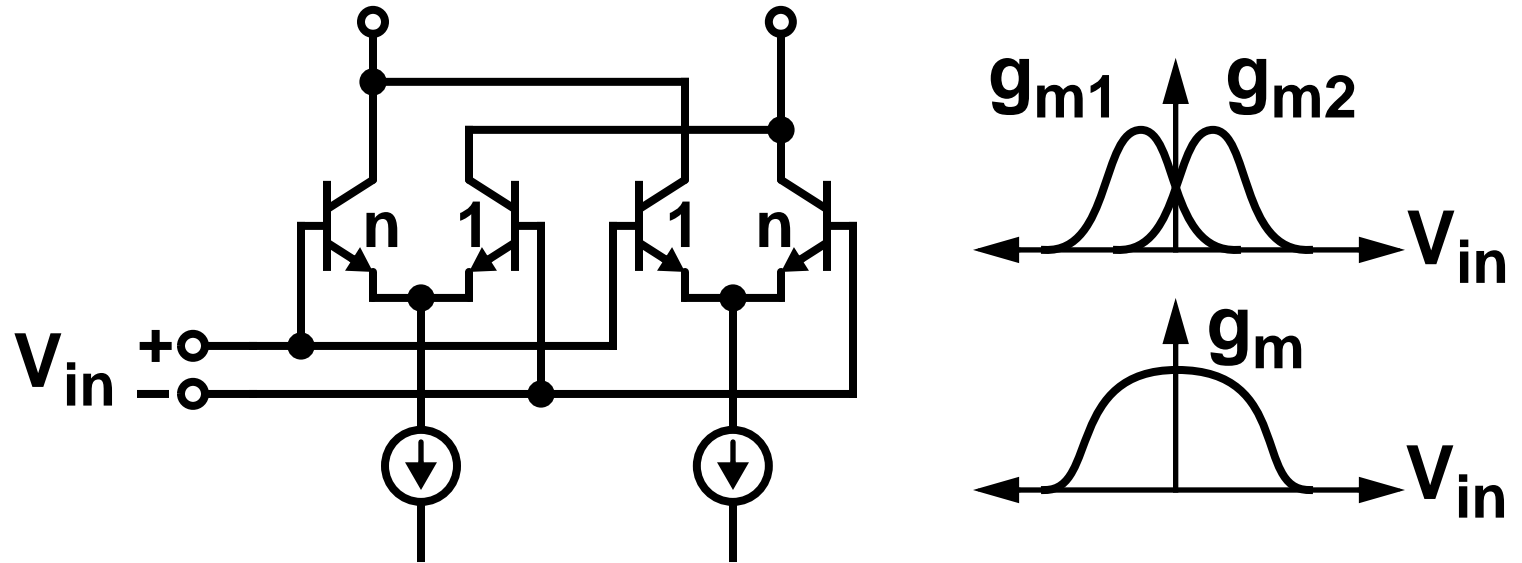
Fold the Output Current



- + Increased headroom for differential pair
- + Increased output resistance

Multi-Tanh Doublet

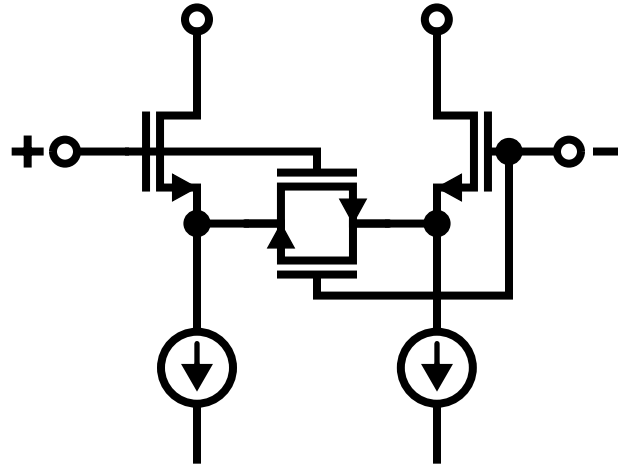
[Gilbert JSSC Dec. 1998]



- With BJTs, ratioing the emitter areas creates a well-controlled offset
- With the right offset, the cubic term in the nonlinearity is zero!

$$n = 2 + \sqrt{3} = 3.73 \approx 15/4$$

MOS Quad



- **Supposedly can get less distortion than a degenerated differential pair by fiddling with W/L**

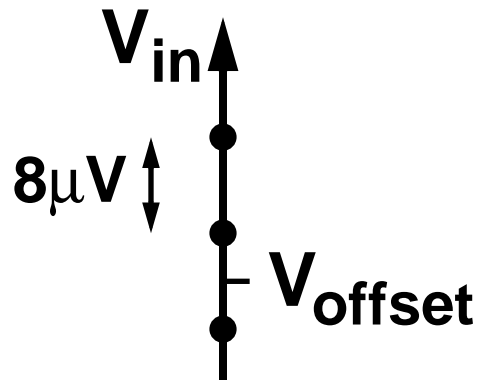
What You Learned Today

- 1 Operation of Example Comparator Circuit**
- 2 Regeneration Time Constant τ**
- 3 Metastability, Probability of Error**
- 4 Offset, Dynamic Offset, Auto-zeroing**
- 5 Flash ADC**
- 6 A Bunch of Transconductor Circuits**

Supplementary Slides (Regarding Metastability)

Quantized Charge Helps?

- If $C = 20$ fF, then 1 electron yields $8 \mu\text{V}$
- $V_{\text{in}} = 2$ nV and hence metastability impossible?

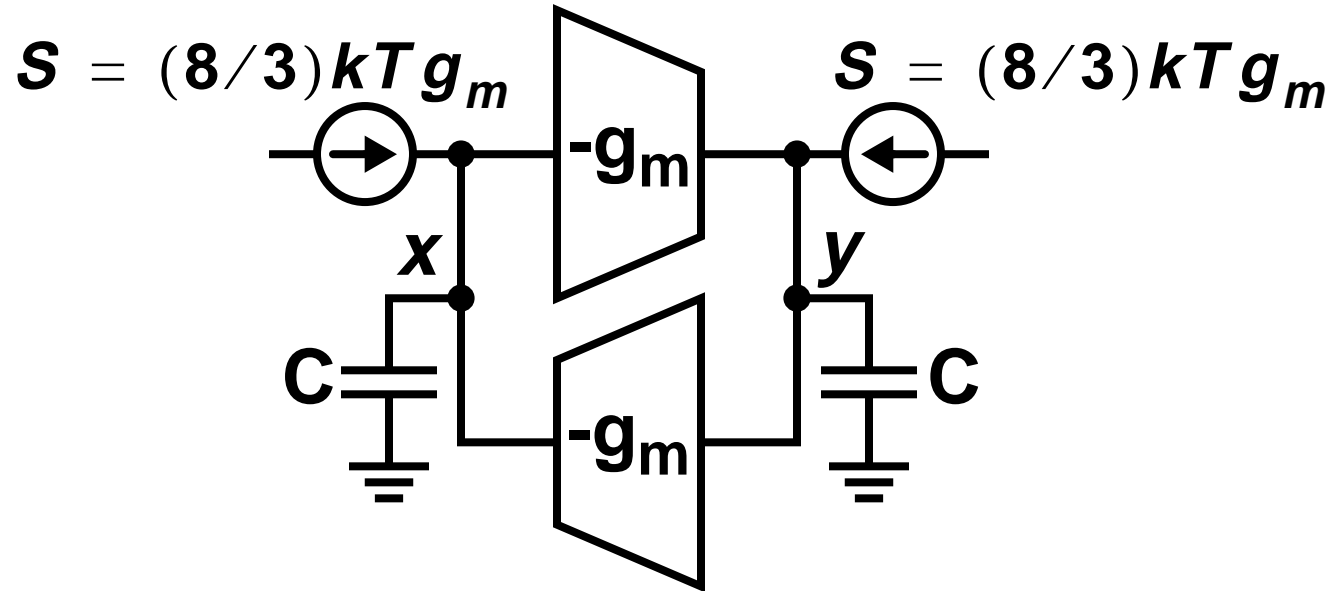


- + Unless V_{offset} is within 2 nV of one of the discrete V_{in} levels, metastability can't happen
- But if V_{offset} is within 2 nV of an allowed V_{in} level, metastability will be abnormally frequent
- Offset drift will tend to make metastability appear/disappear sporadically (?)

Noise Helps?

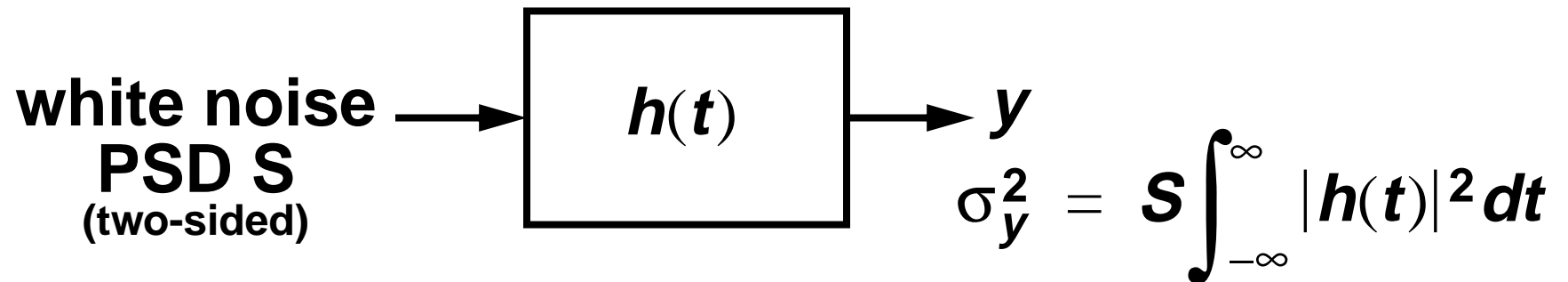
- $kT/C = 500 \mu\text{V}$, so it is impossible to guarantee that metastability will result even if $V_{\text{in}} = 0$
- + Noise does help a comparator resolve if it is metastable
- But for any given noise (random initial condition), there is always an input which results in metastability
- Noise makes it hard to set initial conditions that will result in metastability, but does not reduce the probability of error

What About Noise During Regeneration?



- Noise from the g_m s prevents metastability?

Math Break: Filtered White Noise

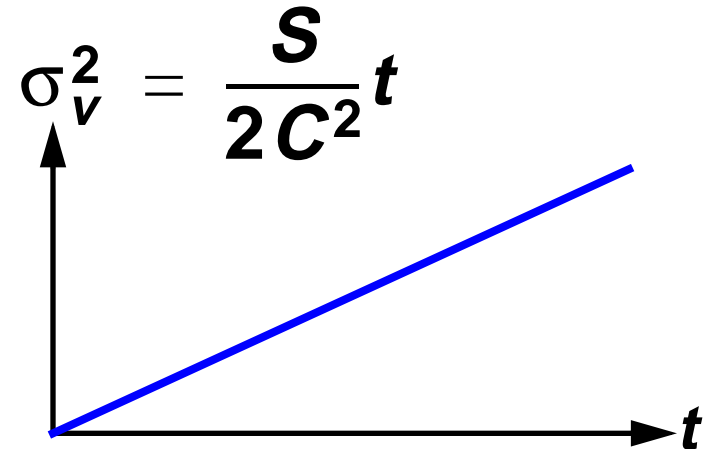
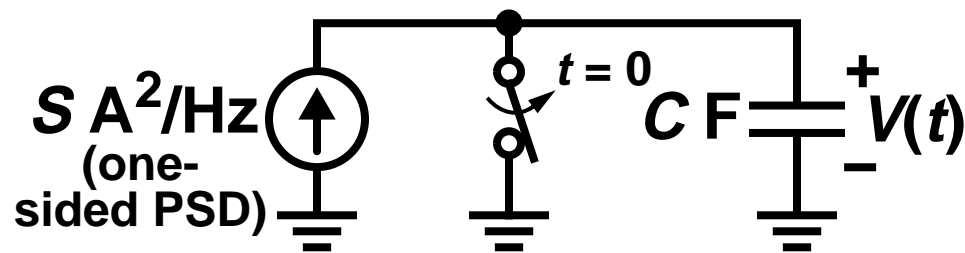


- The power of the output is the product of the PSD and the power gain of the filter

- Example: $h(t) = \begin{cases} 1 & 0 \leq t \leq T \\ 0 & \text{otherwise} \end{cases}$

$$\Rightarrow \sigma_y^2 = ST$$

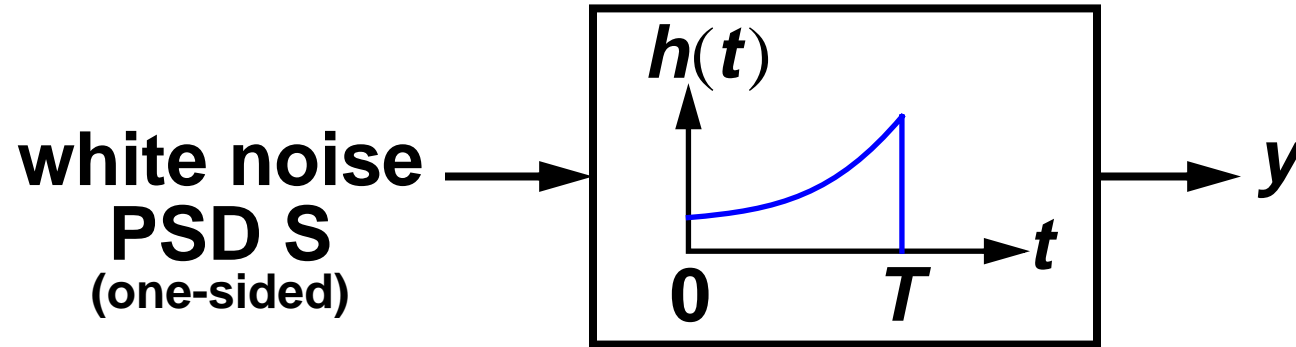
Circuits Application: Integrated White Noise



- Variance of V increases linearly with time
- “Random Walk” or “Brownian Motion”
For any given increment of time Δt , the change in V is a random variable with constant variance

$$\delta(t) \equiv V(t) - V(t - \Delta t) \Rightarrow \sigma_{\delta}^2 = \text{constant}$$

Today's Application



$$h(t) = \begin{cases} e^{t/\tau} & 0 \leq t \leq T \\ 0 & \text{otherwise} \end{cases}$$

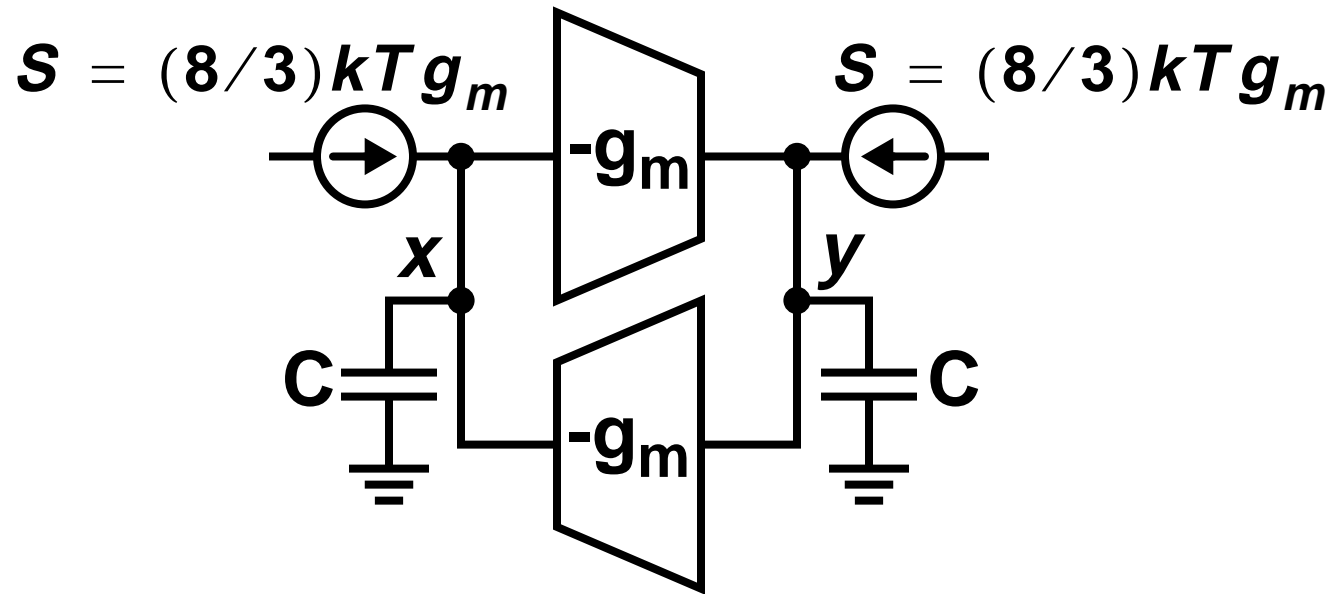
$$\sigma_y^2 = \frac{S\tau}{4} \left(e^{\frac{2T}{\tau}} - 1 \right)$$

Another Math Fact: PDF of a Sum

- Suppose x and y are two independent random variables with probability density functions (PDFs) $\rho_x(x)$ and $\rho_y(y)$
- Then the PDF of their sum is the convolution of the individual PDFs

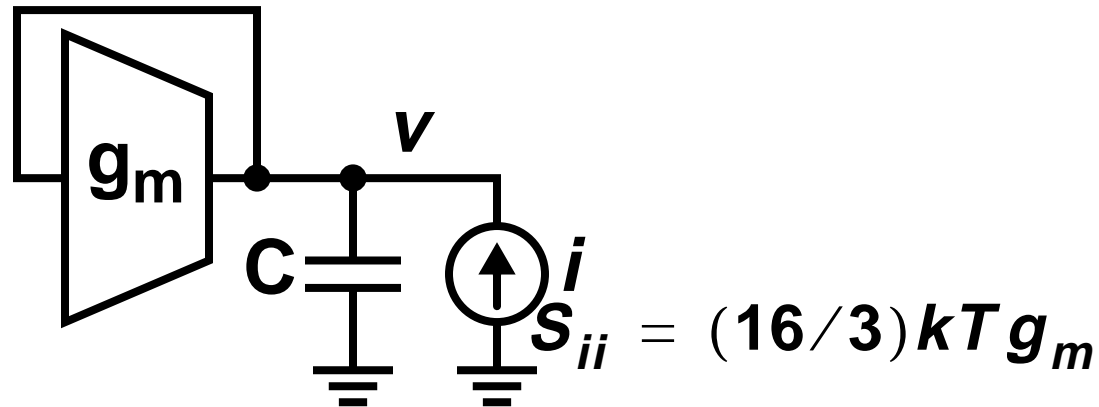
$$\mathbf{z} = \mathbf{x} + \mathbf{y} \Rightarrow \rho_z(\mathbf{z}) = \int_{-\infty}^{\infty} \rho_x(\mathbf{x}) \rho_y(\mathbf{z} - \mathbf{x}) d\mathbf{x}$$

Back to Circuits



- Noise from the g_m s prevents metastability?

Differential Circuit

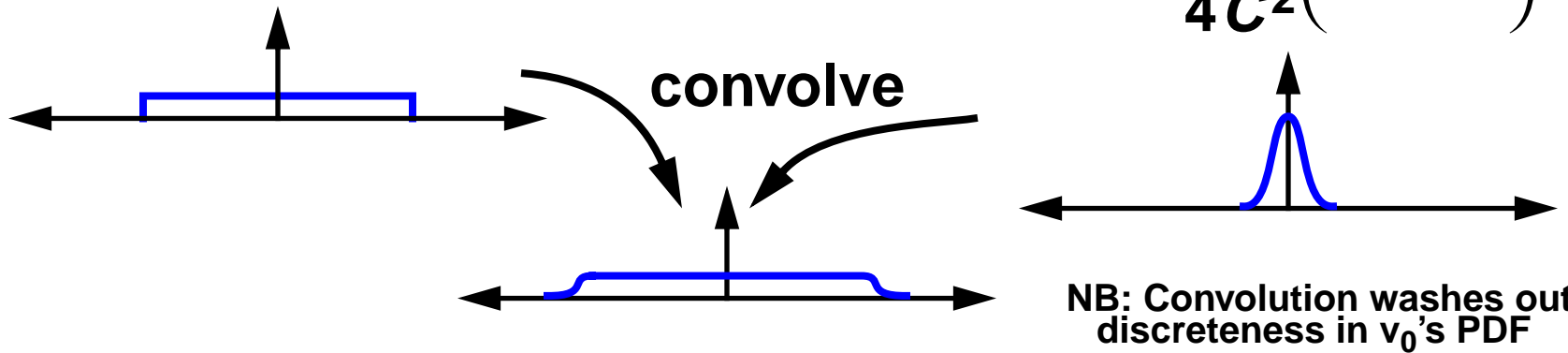


$$v(t) = v_0 e^{t/\tau} + \frac{1}{C} \int_0^t i(\xi) e^{\frac{t-\xi}{\tau}} d\xi$$

Random variable with the same PDF as v_0 , just scaled by $e^{t/\tau}$

r.v. with variance

$$\sigma^2 = \frac{S_{ii}\tau}{4C^2} \left(e^{\frac{2t}{\tau}} - 1 \right)$$



Making Numbers...

- Assume $g_m = 1 \text{ mA/V}$, $C = 20 \text{ fF}$, $t = 400 \text{ ps}$
 $\Rightarrow \tau = 20 \text{ ps}$; 20τ to resolve
- If v_0 uniformly distributed in $[-2,+2] \text{ mV}$,
then 1st term is uniformly distributed in
 $[-1,+1] \text{ MV}$
- Standard deviation of 2nd term is 250 kV
Equivalent to a 0.5-mV initial condition
- Noise during regeneration helps when the input
is known to be small, but is usually negligible
compared to the exponential growth of the initial
conditions